32-bit ARMTM CortexTM-M3 based Microcontroller



MB9AF311K, MB9AF312K

■ DESCRIPTION

The MB9A310K Series are a highly integrated 32-bit microcontrollers dedicated for embedded controllers with high-performance and low cost.

These series are based on the ARM Cortex-M3 Processor with on-chip Flash memory and SRAM, and has peripheral functions such as Motor Control Timers, ADCs and Communication Interfaces (USB, UART, CSIO, I²C, LIN).

The products which are described in this data sheet are placed into TYPE5 product categories in "FM3 Famliy PERIPHERAL MANUAL".

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■ FEATURES

- 32-bit ARM Cortex-M3 Core
 - Processor version: r2p1
 - Up to 40MHz Frequency Operation
 - Integrated Nested Vectored Interrupt Controller (NVIC): 1 NMI (non-maskable interrupt) and 48 peripheral interrupts and 16 priority levels
 - 24-bit System timer (Sys Tick): System timer for OS task management

On-chip Memories

[Flash memory]

This Series are based on two independent on-chip Flash memories.

- MainFlash
 - · Up to 128Kbyte
 - Read cycle: 0 wait-cycle
 - · Security function for code protection
- WorkFlash
 - 32Kbyte
 - Read cycle: 0 wait-cycle
 - Security function is shared with code protection

[SRAM]

This Series contain a total of up to 16Kbyte on-chip SRAM memories. This is composed of two independent SRAM (SRAM0, SRAM1) . SRAM0 is connected to I-code bus or D-code bus of Cortex-M3 core. SRAM1 is connected to System bus.

SRAM0 : 8 KbyteSRAM1 : 8 Kbyte

USB Interface

USB interface is composed of Function and Host.

[USB function]

- · USB2.0 Full-Speed supported
- · Max 6 EndPoint supported
 - EndPoint 0 is control transfer
 - EndPoint 1, 2 can be selected Bulk-transfer, Interrupt-transfer or Isochronous-transfer
 - EndPoint 3 to 5 can be selected Bulk-transfer or Interrupt-transfer
- EndPoint 1 to 5 is comprised Double Buffer

[USB host]

- · USB2.0 Full/Low-speed supported
- · Bulk-transfer, interrupt-transfer and Isochronous-transfer support
- · USB Device connected/dis-connected automatically detect
- · IN/OUT token handshake packet automatically
- · Max 256-byte packet-length supported
- · Wake-up function supported

Multi-function Serial Interface (Max 4channels)

- 2 channels with 16-steps × 9-bits FIFO (ch.0, ch.1), 2 channels without FIFO (ch.3, ch.5)
- Operation mode is selectable from the followings for each channel.

(In ch.5, only UART and LIN are available.)

- UART
- · CSIO
- LIN
- I^2C

[UART]

- · Full-duplex double buffer
- · Selection with or without parity supported
- · Built-in dedicated baud rate generator
- · External clock available as a serial clock
- Hardware Flow control: Automatically control the transmission by CTS/RTS (only ch.4)
- · Various error detect functions available (parity errors, framing errors, and overrun errors)

[CSIO]

- Full-duplex double buffer
- · Built-in dedicated baud rate generator
- · Overrun error detect function available

[LIN]

- LIN protocol Rev.2.1 supported
- · Full-duplex double buffer
- · Master/Slave mode supported
- LIN break field generate (can be changed 13 to 16-bit length)
- LIN break delimiter generate (can be changed 1 to 4-bit length)
- · Various error detect functions available (parity errors, framing errors, and overrun errors)

[I²C]

Standard mode (Max 100kbps) / High-speed mode (Max 400kbps) supported

DMA Controller (4channels)

DMA Controller has an independent bus for CPU, so CPU and DMA Controller can process simultaneously.

- · 8 independently configured and operated channels
- · Transfer can be started by software or request from the built-in peripherals
- Transfer address area: 32-bit (4Gbyte)
- Transfer mode: Block transfer/Burst transfer/Demand transfer
- · Transfer data type: byte/half-word/word
- Transfer block count: 1 to 16
- · Number of transfers: 1 to 65536

A/D Converter (Max 8channels)

[12-bit A/D Converter]

- Successive Approximation Register type
- Built-in 2unit
- Conversion time: 1.0µs@5V
- Priority conversion available (priority at 2levels)
- · Scanning conversion mode
- Built-in FIFO for conversion data storage

(for SCAN conversion: 16steps, for Priority conversion: 4steps)

Base Timer (Max 8channels)

Operation mode is selectable from the followings for each channel.

- 16-bit PWM timer
- · 16-bit PPG timer
- 16/32-bit reload timer
- 16/32-bit PWC timer

General Purpose I/O Port

This series can use its pins as General Purpose I/O ports when they are not used for external bus or peripherals. Moreover, the port relocate function is built in. It can set which I/O port the peripheral function can be allocated.

- · Capable of pull-up control per pin
- · Capable of reading pin level directly
- Built-in the port relocate function
- Up 36 fast General Purpose I/O Ports
- Some pin is 5V tolerant I/O.

See "■PIN DESCRIPTION" to confirm the corresponding pins.

Multi-function Timer

The Multi-function timer is composed of the following blocks.

- 16-bit free-run timer × 3ch.
- Input capture × 4ch.
- Output compare × 6ch.
- A/D activating compare × 3ch.
- Waveform generator × 3ch.
- 16-bit PPG timer \times 3ch.

The following function can be used to achieve the motor control.

- · PWM signal output function
- · DC chopper waveform output function
- · Dead time function
- · Input capture function
- · A/D convertor activate function
- DTIF (Motor emergency stop) interrupt function

Real-time clock (RTC)

The Real-time clock can count Year/Month/Day/Hour/Minute/Second/A day of the week from 01 to 99.

- Interrupt function with specifying date and time (Year/Month/Day/Hour/Minute/Second/A day of the week.) is available. This function is also available by specifying only Year, Month, Day, Hour or Minute.
- Timer interrupt function after set time or each set time.
- · Capable of rewriting the time with continuing the time count.
- · Leap year automatic count is available.

Quadrature Position/Revolution Counter (QPRC)

The Quadrature Position/Revolution Counter (QPRC) is used to measure the position of the position encoder. Moreover, it is possible to use up/down counter.

- The detection edge of the three external event input pins AIN, BIN and ZIN is configurable.
- 16-bit position counter
- 16-bit revolution counter
- Two 16-bit compare registers

• Dual Timer (32/16-bit Down Counter)

The Dual Timer consists of two programmable 32/16-bit down counters. Operation mode is selectable from the followings for each channel.

- Free-running
- Periodic (=Reload)
- · One-shot

Watch Counter

The Watch counter is used for wake up from Low Power Consumption mode.

• Interval timer: up to 64s (Max) @ Sub Clock: 32.768kHz

External Interrupt Controller Unit

- Up to 6 external interrupt input pin
- Include one non-maskable interrupt (NMI)

Watchdog Timer (2channels)

A watchdog timer can generate interrupts or a reset when a time-out value is reached.

This series consists of two different watchdogs, a "Hardware" watchdog and a "Software" watchdog.

"Hardware" watchdog timer is clocked by low-speed internal CR oscillator. Therefore, "Hardware" watchdog is active in any power saving mode except RTC and STOP and Deep stand-by RTC and Deep stand-by STOP.

• CRC (Cyclic Redundancy Check) Accelerator

The CRC accelerator helps a verify data transmission or storage integrity.

CCITT CRC16 and IEEE-802.3 CRC32 are supported.

- CCITT CRC16 Generator Polynomial: 0x1021
- IEEE-802.3 CRC32 Generator Polynomial: 0x04C11DB7

Clock and Reset

[Clocks]

Five clock sources (2 external oscillators, 2 internal CR oscillator, and Main PLL) that are dynamically selectable.

Main Clock : 4MHz to 48MHz
 Sub Clock : 32.768kHz
 High-speed internal CR Clock : 4MHz
 Low-speed internal CR Clock : 100kHz

· Main PLL Clock

[Resets]

- Reset requests from INITX pin
- · Power on reset
- · Software reset
- · Watchdog timers reset
- Low-voltage detector reset
- Clock supervisor reset

Clock Super Visor (CSV)

Clocks generated by internal CR oscillators are used to supervise abnormality of the external clocks.

- External OSC clock failure (clock stop) is detected, reset is asserted.
- External OSC frequency anomaly is detected, interrupt or reset is asserted.

Low-Voltage Detector (LVD)

This Series include 2-stage monitoring of voltage on the VCC pins. When the voltage falls below the voltage has been set, Low-Voltage Detector generates an interrupt or reset.

- · LVD1: error reporting via interrupt
- LVD2: auto-reset operation

Low Power Consumption Mode

Six Low Power Consumption modes supported.

- · SLEEP
- · TIMER
- · RTC
- STOP
- · Deep stand-by RTC
- · Deep stand-by STOP

Debug

Serial Wire JTAG Debug Port (SWJ-DP)

Power Supply

• Wide range voltage : VCC = 2.7V to 5.5V

• Power supply for USB I/O : USBVCC0 = 3.0V to 3.6V (when USB is used) = 2.7V to 5.5V (when GPIO is used)

■ PRODUCT LINEUP

Memory size

Produ	ct name	MB9AF311K	MB9AF312K
On-chip	MainFlash	64Kbyte	128Kbyte
Flash	WorkFlash	32Kbyte	32Kbyte
0 1:	SRAM0	8Kbyte	8Kbyte
On-chip SRAM	SRAM1	8Kbyte	8Kbyte
	Total	16Kbyte	16Kbyte

Function

• I diletion			MB9AF311K
	Product name		MB9AF312K
Din cou	Pin count		48/52
r III Cou	Fill Coulit		Cortex-M3
CPU	Freq.		40MHz
			2.7V to 5.5V
Powers	supply voltage	erange	(USBVCC:3.0V to 3.6V)
USB2.0) (Function/Ho	ost)	1ch. (Max)
DMAC			4ch. (Max)
	unction Serial /CSIO/LIN/I ²		4ch. (Max) with 16-steps × 9-bits FIFO : ch.0, ch.1 without FIFO : ch.3, ch.5 (In ch.5, only UART and LIN are available.)
Base Ti	mer Reload timer/	PWM/PPG)	8ch. (Max)
(r wc/	A/D activation compare	3ch.	
	Input capture	4ch.	
MF- Timer	Free-run timer	3ch.	1 unit (Max)
	Output compare	6ch.	
	Waveform generator	3ch.	
	PPG	3ch.	
QPRC			1ch. (Max)
Dual Ti			1 unit
	ne clock		1 unit
	Counter		1 unit
	ccelerator		Yes
	og timer		1ch. (SW) + 1ch. (HW)
	l Interrupts		$6pins (Max) + NMI \times 1$
	l Purpose I/O	ports	36pins (Max)
	A/D converter		8ch. (2 units)
	Clock Super Vi		Yes
LVD (Low-Voltage Detector)			2ch.
Internal			4MHz (±2%)
OSC	Low-sp	eed	100kHz (Typ)
	Function		SWJ-DP

Note: All signals of the peripheral function in each product cannot be allocated by limiting the pins of package. It is necessary to use the port relocate function of the General I/O port according to your function use.

■ PACKAGES

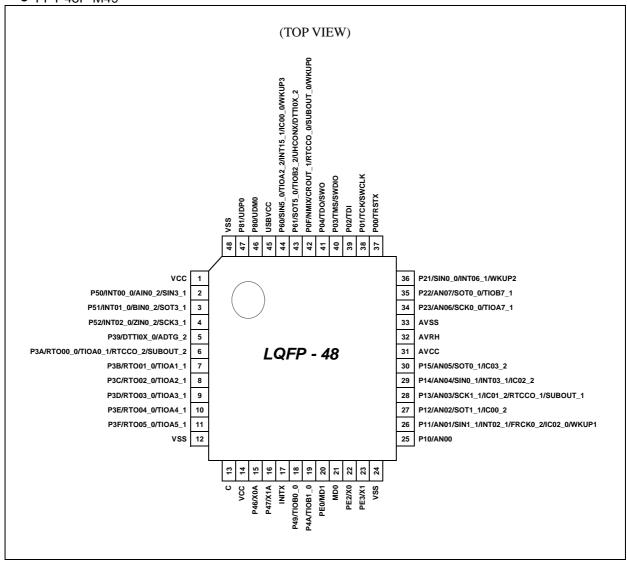
Product name Package	MB9AF311K MB9AF312K
LQFP: FPT-48P-M49 (0.5mm pitch)	O
QFN: LCC-48P-M73 (0.5mm pitch)	O
LQFP: FPT-52P-M02 (0.65mm pitch)	O

O : Supported

Note : See " $\blacksquare PACKAGE \ DIMENSIONS"$ for detailed information on each package.

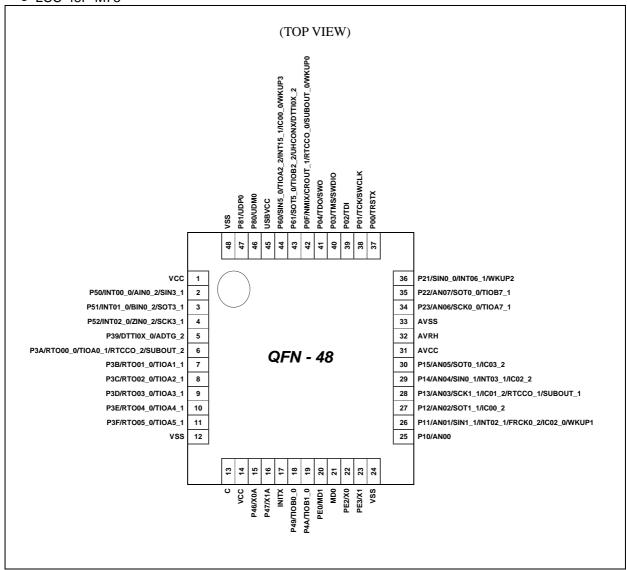
■ PIN ASSIGNMENT

• FPT-48P-M49



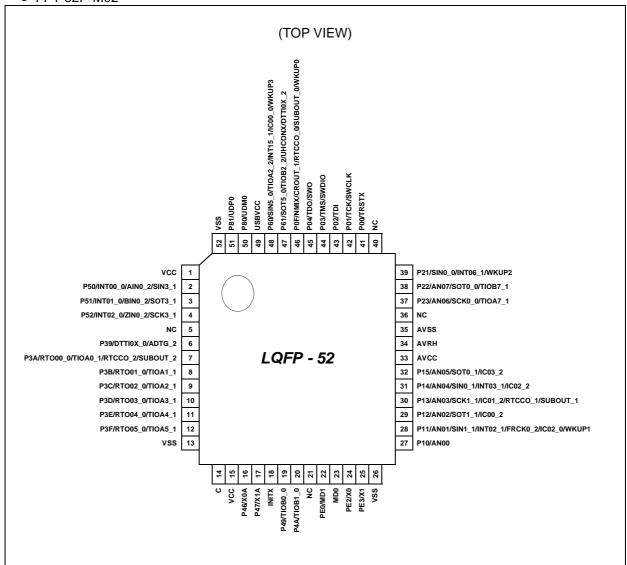
<Note>

• LCC-48P-M73



<Note>

FPT-52P-M02



<Note>

■ PIN DESCRIPTION

Pin	No		I/O circuit	Din state
LQFP-48 QFN-48	LQFP-52	Pin Name	type	Pin state type
1	1	VCC	-	
		P50		
2		INT00_0	T 4	**
2	2	AINO_2	I *	Н
		SIN3_1		
		P51		
2	2	INT01_0	Tu	**
3	3	BINO_2	I *	Н
		SOT3_1		
		P52		
4	4	INT02_0	τ ψ	7.7
4	4	ZIN0_2	I *	Н
		SCK3_1		
-	5	NC	-	-
		P39		
5	6	DTTI0X_0	E	I
		ADTG_2		
		P3A		I
		RTO00_0		
6	7	TIOA0_1	G	
		RTCCO_2		
		SUBOUT_2		
		P3B		
7	8	RTO01_0	G	I
		TIOA1_1		
		P3C		
8	9	RTO02_0	G	I
		TIOA2_1		
		P3D		
9	10	RTO03_0	G	I
		TIOA3_1		
		P3E		
10	11	RTO04_0	G	I
		TIOA4_1		l
		P3F		
11	12	RTO05_0	G	I
		TIOA5_1		
12	13	VSS	-	

Pin	No		I/O circuit	Pin state
LQFP-48 QFN-48	LQFP-52	Pin Name	type	type
13	14	С		-
14	15	VCC		=
		P46	_	
15	16	X0A	D	M
1.0	17	P47	2) Y
16	17	X1A	D	N
17	18	INITX	В	С
18	19	P49	Е	I
16	19	TIOB0_0	Е	1
19	20	P4A	E	I
19	20	TIOB1_0	E	1
-	21	NC	-	-
20	22	PE0	C	P
20	22	MD1		1
21	23	MD0	J	D
22	24	PE2	A	A
22	24	X0	A	A
23	25	PE3	A	В
23	23	X1	A	
24	26	VSS	-	-
25	27	P10	F	K
	27	AN00	•	
		P11		F
		AN01		
		SIN1_1		
26	28	INT02_1	F	
		FRCK0_2		
		IC02_0		
		WKUP1		
		P12		
27	29	AN02	F	K
2,		SOT1_1		11
		IC00_2		
		P13		
		AN03		
28	30	SCK1_1	F	K
		IC01_2		
		RTCCO_1		
		SUBOUT_1		
		P14		
		AN04		
29	31	SIN0_1	F	L
		INT03_1		
		IC02_2		

	No		I/O circuit	Pin state
LQFP-48 QFN-48	LQFP-52	Pin Name	type	type
ζ		P15		
		AN05		
30	32	SOT0_1	F	K
		IC03_2		
31	33	AVCC		_
32	34	AVRH		
33	35	AVSS		
-	36	NC		-
		P23		
		AN06	_	
34	37	SCK0_0	F	K
		 TIOA7_1		
		P22		
25		AN07	-	***
35	38	SOT0_0	F	K
		TIOB7_1		
		P21		
2.5		SINO_0		<i>a</i>
36	39	INT06_1	E	G
		WKUP2		
=	40	NC		-
27	4.1	P00	-	Е
37	41	TRSTX	E	
		P01		
38	42	TCK	E	E
		SWCLK		
20	40	P02	-	
39	43	TDI	E	Е
		P03		
40	44	TMS	E	Е
		SWDIO		
		P04		
41	45	TDO	E	Е
		SWO		
		P0F		
		NMIX		
40	1.	CROUT_1		.
42	46	RTCCO_0	E	J
	-	SUBOUT_0		
		WKUP0		
		P61		
		SOT5_0		
43	47	TIOB2_2	E	I
		UHCONX		
		DTTI0X_2		

Pin	No		I/O circuit	Pin state
LQFP-48 QFN-48	LQFP-52	Pin Name	type	type
		P60		
		SIN5_0		G
44	48	TIOA2_2	I *	
44	46	INT15_1	1"	
		IC00_0		
		WKUP3		
45	49	USBVCC		-
46	50	P80	Н	0
40	30	UDM0	п	U
47	51	P81	Н	0
		UDP0	п	U
48	52	VSS		-

^{*: 5}V tolerant I/O

■ SIGNAL DESCRIPTION

			Pin	No
Module	Pin name	Function	LQFP-48 QFN-48	LQFP-52
ADC	ADTG_2	A/D converter external trigger input pin	5	6
	AN00		25	27
	AN01	7	26	28
	AN02	7	27	29
	AN03	A/D converter analog input pin.	28	30
	AN04	ANxx describes ADC ch.xx.	29	31
	AN05		30	32
	AN06		34	37
	AN07		35	38
Base Timer	TIOA0_1	Base timer ch.0 TIOA pin	6	7
0	TIOB0_0	Base timer ch.0 TIOB pin	18	19
Base Timer	TIOA1_1	Base timer ch.1 TIOA pin	7	8
1	TIOB1_0	Base timer ch.1 TIOB pin	19	20
Base Timer	TIOA2_1	Page times of 2 TIOA sin	8	9
2	TIOA2_2	Base timer ch.2 TIOA pin	44	48
	TIOB2_2	Base timer ch.2 TIOB pin	43	47
Base Timer 3	TIOA3_1	Base timer ch.3 TIOA pin	9	10
Base Timer 4	TIOA4_1	Base timer ch.4 TIOA pin	10	11
Base Timer 5	TIOA5_1	Base timer ch.5 TIOA pin	11	12
Base Timer	TIOA7_1	Base timer ch.7 TIOA pin	34	37
7	TIOB7_1	Base timer ch.7 TIOB pin	35	38
Debugger	SWCLK	Serial wire debug interface clock input pin	38	42
	SWDIO	Serial wire debug interface data input/output pin	40	44
	SWO	Serial wire viewer output pin	41	45
	TCK	J-TAG test clock input pin	38	42
	TDI	J-TAG test data input pin	39	43
	TDO	J-TAG debug data output pin	41	45
	TMS	J-TAG test mode state input/output pin	40	44
	TRSTX	J-TAG test reset Input pin	37	41
External	INT00_0	External interrupt request 00 input pin	2	2
Interrupt	INT01_0	External interrupt request 01 input pin	3	3
	INT02_0	Entermal interment required 02 in and air	4	4
	INT02_1	External interrupt request 02 input pin	26	28
	INT03_1	External interrupt request 03 input pin	29	31
	INT06_1	External interrupt request 06 input pin	36	39
	INT15_1	External interrupt request 15 input pin	44	48
	NMIX	Non-Maskable Interrupt input pin	42	46

			Pin	No
Module	Pin name	Function	LQFP-48	LQFP-52
			QFN-48	
GPIO	P00		37	41
	P01		38	42
	P02	General-purpose I/O port 0	39	43
	P03	Concrat purpose 1/0 port 0	40	44
	P04		41	45
	P0F		42	46
	P10		25	27
	P11		26	28
	P12	General-purpose I/O port 1	27	29
	P13	Seneral pulpose I o port I	28	30
	P14		29	31
	P15		30	32
	P21		36	39
	P22	General-purpose I/O port 2	35	38
	P23		34	37
	P39	39	5	6
	P3A		6	7
	P3B		7	8
	P3C	General-purpose I/O port 3	8	9
	P3D		9	10
	P3E		10	11
	P3F		11	12
	P46		15	16
	P47	G 1	16	17
	P49	General-purpose I/O port 4	18	19
	P4A		19	20
	P50		2	2
	P51	General-purpose I/O port 5	3	3
	P52		4	4
	P60	Company and I/O and C	44	48
	P61	General-purpose I/O port 6	43	47
	P80	Consultation I/O and 0	46	50
	P81	General-purpose I/O port 8	47	51
	PE0		20	22
	PE2	General-purpose I/O port E	22	24
	PE3	7	23	25

			Pin No.	
Module	Pin name	Function	LQFP-48 QFN-48	LQFP-52
Multi-	SINO_0	Multi-function serial interface ch.0 input	36	39
function	SIN0_1	pin	29	31
Serial 0	SOT0_0 (SDA0_0)	Multi-function serial interface ch.0 output pin. This pin operates as SOT0 when it is used	35	38
	SOT0_1 (SDA0_1)	in a UART/CSIO/LIN (operation modes 0 to 3) and as SDA0 when it is used in an I ² C (operation mode 4).	30	32
	SCK0_0 (SCL0_0)	Multi-function serial interface ch.0 clock I/O pin. This pin operates as SCK0 when it is used in a CSIO (operation modes 2) and as SCL0 when it is used in an I ² C (operation mode 4).	34	37
Multi- function	SIN1_1	Multi-function serial interface ch.1 input pin	26	28
Serial 1	SOT1_1 (SDA1_1)	Multi-function serial interface ch.1 output pin. This pin operates as SOT1 when it is used in a UART/CSIO/LIN (operation modes 0 to 3) and as SDA1 when it is used in an I ² C (operation mode 4).	27	29
	SCK1_1 (SCL1_1)	Multi-function serial interface ch.1 clock I/O pin. This pin operates as SCK1 when it is used in a CSIO (operation modes 2) and as SCL1 when it is used in an I ² C (operation mode 4).	28	30

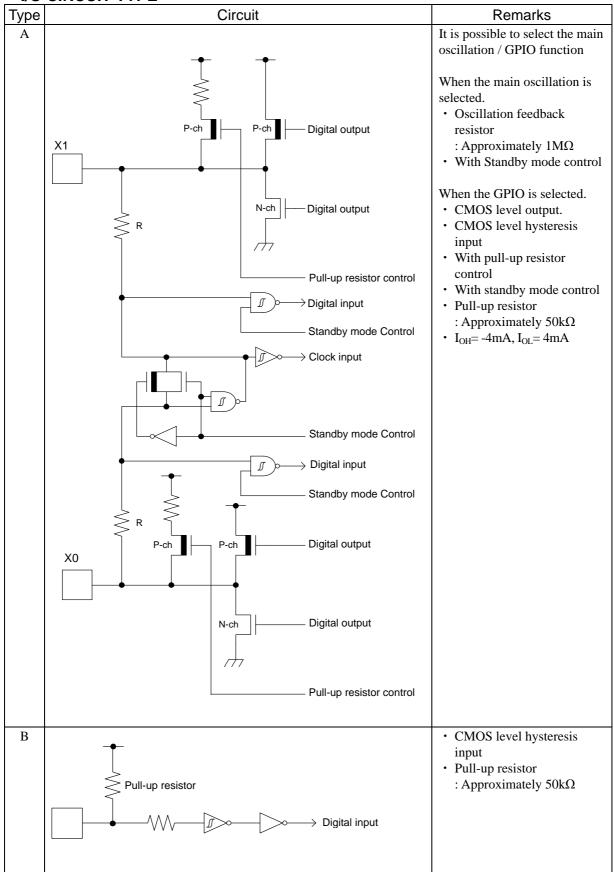
			Pin No.	
Module	Pin name	Function	LQFP-48 QFN-48	LQFP-52
Multi- function	SIN3_1	Multi-function serial interface ch.3 input pin	2	2
Serial 3	SOT3_1 (SDA3_1)	Multi-function serial interface ch.3 output pin. This pin operates as SOT3 when it is used in a UART/CSIO/LIN (operation modes 0 to 3) and as SDA3 when it is used in an I ² C (operation mode 4).	3	3
	SCK3_1 (SCL3_1)	Multi-function serial interface ch.3 clock I/O pin. This pin operates as SCK3 when it is used in a CSIO (operation modes 2) and as SCL3 when it is used in an I ² C (operation mode 4).	4	4
Multi- function	SIN5_0	Multi-function serial interface ch.5 input pin	44	48
Serial 5	SOT5_0	Multi-function serial interface ch.5 output pin. This pin operates as SOT5 when it is used in a UART/LIN (operation modes 0, 1, 3).	43	47

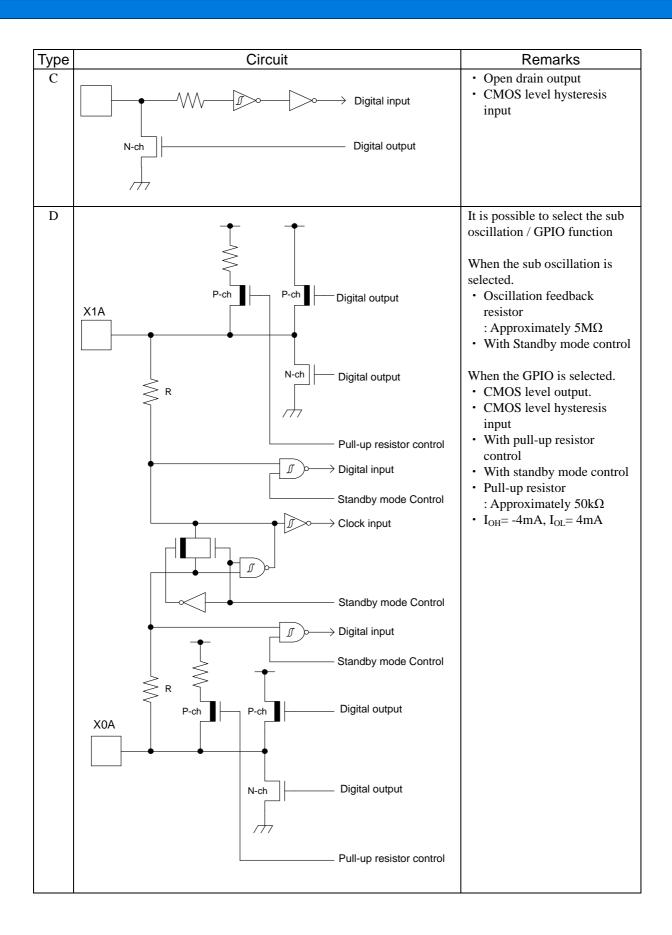
				No
Module	Pin name	Function	LQFP-48 QFN-48	LQFP-52
Multi-	DTTI0X_0	Input signal controlling wave form	5	6
function Timer	DTTI0X_2	generator outputs RTO00 to RTO05 of multi-function timer 0.	43	47
0	FRCK0_2	16-bit free-run timer ch.0 external clock input pin	26	28
	IC00_0		44	48
	IC00_2	16-bit input capture ch.0 input pin of multi-function timer 0. ICxx describes channel number.	27	29
	IC01_2		28	30
	IC02_0		26	28
	IC02_2		29	31
	IC03_2		30	32
	RTO00_0 (PPG00_0)	Wave form generator output pin of multi-function timer 0. This pin operates as PPG00 when it is used in PPG0 output modes.	6	7
	RTO01_0 (PPG00_0)	Wave form generator output pin of multi-function timer 0. This pin operates as PPG00 when it is used in PPG0 output modes.	7	8
	RTO02_0 (PPG02_0)	Wave form generator output pin of multi-function timer 0. This pin operates as PPG02 when it is used in PPG0 output modes.	8	9
	RTO03_0 (PPG02_0)	Wave form generator output pin of multi-function timer 0. This pin operates as PPG02 when it is used in PPG0 output modes.	9	10
	RTO04_0 (PPG04_0)	Wave form generator output pin of multi-function timer 0. This pin operates as PPG04 when it is used in PPG0 output modes.	10	11
	RTO05_0 (PPG04_0)	Wave form generator output pin of multi-function timer 0. This pin operates as PPG04 when it is used in PPG0 output modes.	11	12

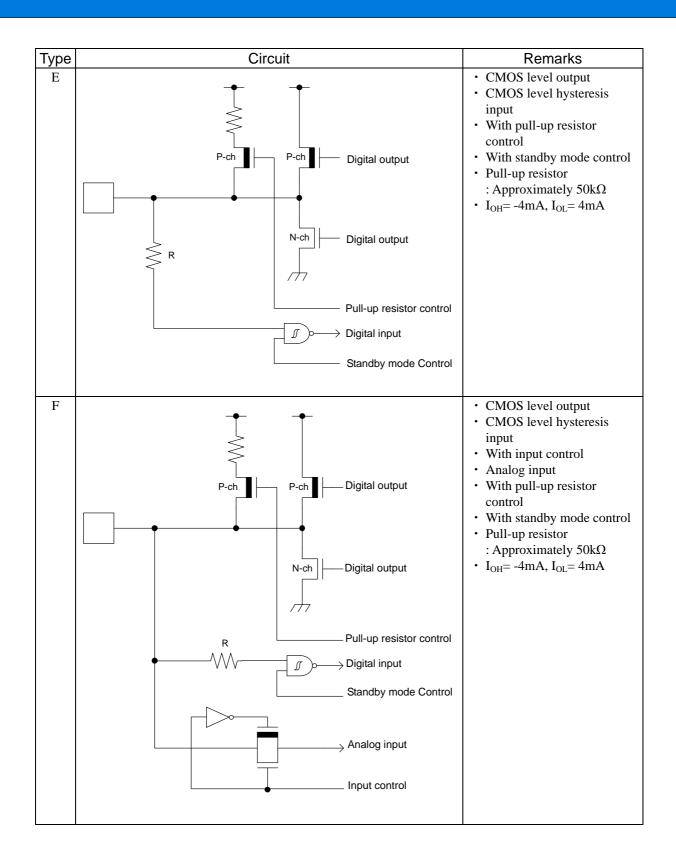
			Pin	n No	
Module	Pin name	Function	LQFP-48 QFN-48	LQFP-52	
Quadrature Position/	AIN0_2	QPRC ch.0 AIN input pin	2	2	
Revolution Counter	BIN0_2	QPRC ch.0 BIN input pin	3	3	
0	ZIN0_2	QPRC ch.0 ZIN input pin	4	4	
Real-time	RTCCO_0	0.5	42	46	
clock	RTCCO_1	0.5 seconds pulse output pin of Real-time	28	30	
	RTCCO_2	Clock	6	7	
	SUBOUT_0		42	46	
	SUBOUT_1	Sub clock output pin	28	30	
	SUBOUT_2	7	6	7	
Low Power Consumption	WKUP0	Deep stand-by mode return signal input pin 0	42	46	
Mode WKUP1 Deep pin 1	Deep stand-by mode return signal input pin 1	26	28		
	WKUP2	Deep stand-by mode return signal input pin 2	36	39	
	WKUP3	Deep stand-by mode return signal input pin 3	44	48	
USB	UDM0	USB ch.0 function/host D - pin	46	50	
	UDP0	USB ch.0 function/host D + pin	47	51	
	UHCONX	USB external pull-up control pin	43	47	

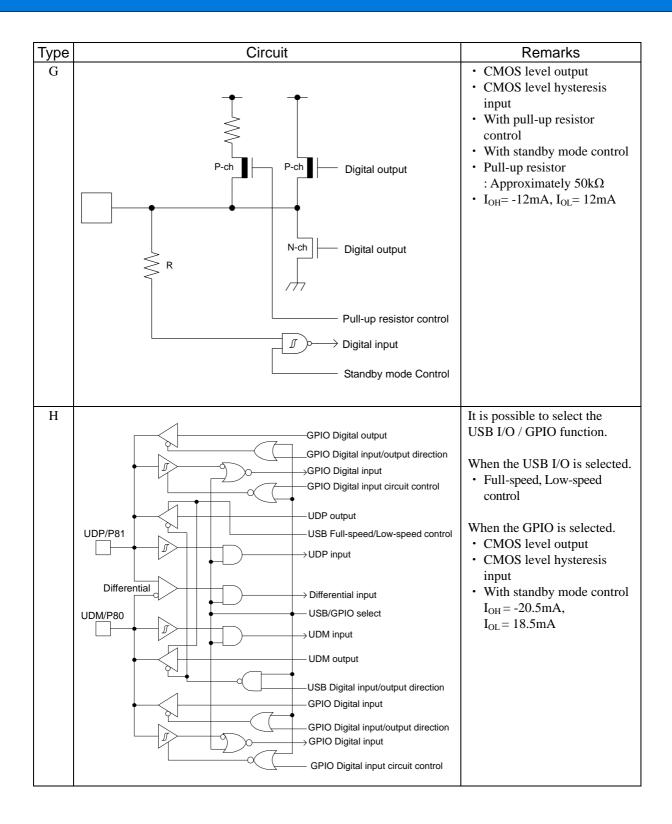
			Pin	No
Module	Pin name	Function	LQFP-48 QFN-48	LQFP-52
RESET	INITX	External Reset Input pin. A reset is valid when INITX="L".	17	18
Mode	MD0	Mode 0 pin. During normal operation, MD0="L" must be input. During serial programming to Flash memory, MD0="H" must be input.	During serial programming to mory, MD0="H" must be input.	
	MD1	Mode 1 pin. During serial programming to Flash memory, MD1="L" must be input.	20	22
POWER	VCC	Power supply Pin	1	1
	VCC	Power supply Pin	14	15
	USBVCC	3.3V Power supply port for USB I/O	45	49
GND	D VSS GND Pin 12		12	13
	VSS	GND Pin	24	26
	VSS GND Pin		48	52
CLOCK	X0	Main clock (oscillation) input pin	22	24
	X0A	Sub clock (oscillation) input pin	15	16
	X1	Main clock (oscillation) I/O pin	23	25
	X1A	Sub clock (oscillation) I/O pin	16	17
	CROUT_1	Internal CR-osc clock output port		46
ADC POWER	AVCC	A/D converter analog power pin	31	33
	AVRH	A/D converter analog reference voltage input pin	32	34
ADC GND	AVSS	A/D converter GND pin	33	35
C pin	C	Power stabilization capacity pin	13	14
NC pin	NC	NC pin. NC pin should be kept open.	-	5
	NC	NC pin. NC pin should be kept open.	-	21
	NC	NC pin. NC pin should be kept open.	-	36
	NC	NC pin. NC pin should be kept open.	-	40

■ I/O CIRCUIT TYPE









Туре	Circuit	Remarks
I	P-ch Digital output R Pull-up resistor control Digital input Standby mode Control	 CMOS level output CMOS level hysteresis input 5V tolerant With pull-up resistor control With standby mode control Pull-up resistor Approximately 50kΩ I_{OH}= -4mA, I_{OL}= 4mA Available to control of PZR registers.
J	Mode input	CMOS level hysteresis input

■ HANDLING PRECAUTIONS

Any semiconductor devices have inherently a certain rate of failure. The possibility of failure is greatly affected by the conditions in which they are used (circuit conditions, environmental conditions, etc.). This page describes precautions that must be observed to minimize the chance of failure and to obtain higher reliability from your FUJITSU SEMICONDUCTOR semiconductor devices.

1. Precautions for Product Design

This section describes precautions when designing electronic equipment using semiconductor devices.

· Absolute Maximum Ratings

Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of certain established limits, called absolute maximum ratings. Do not exceed these ratings.

Recommended Operating Conditions

Recommended operating conditions are normal operating ranges for the semiconductor device. All the device's electrical characteristics are warranted when operated within these ranges.

Always use semiconductor devices within the recommended operating conditions. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their sales representative beforehand.

· Processing and Protection of Pins

These precautions must be followed when handling the pins which connect semiconductor devices to power supply and input/output functions.

(1) Preventing Over-Voltage and Over-Current Conditions

Exposure to voltage or current levels in excess of maximum ratings at any pin is likely to cause deterioration within the device, and in extreme cases leads to permanent damage of the device. Try to prevent such overvoltage or over-current conditions at the design stage.

(2) Protection of Output Pins

Shorting of output pins to supply pins or other output pins, or connection to large capacitance can cause large current flows. Such conditions if present for extended periods of time can damage the device.

Therefore, avoid this type of connection.

(3) Handling of Unused Input Pins

Unconnected input pins with very high impedance levels can adversely affect stability of operation. Such pins should be connected through an appropriate resistance to a power supply pin or ground pin.

· Latch-up

Semiconductor devices are constructed by the formation of P-type and N-type areas on a substrate. When subjected to abnormally high voltages, internal parasitic PNPN junctions (called thyristor structures) may be formed, causing large current levels in excess of several hundred mA to flow continuously at the power supply pin. This condition is called latch-up.

CAUTION: The occurrence of latch-up not only causes loss of reliability in the semiconductor device, but can cause injury or damage from high heat, smoke or flame. To prevent this from happening, do the following:

- (1) Be sure that voltages applied to pins do not exceed the absolute maximum ratings. This should include attention to abnormal noise, surge levels, etc.
- (2) Be sure that abnormal current flows do not occur during the power-on sequence.

Code: DS00-00004-1Ea



Observance of Safety Regulations and Standards

Most countries in the world have established standards and regulations regarding safety, protection from electromagnetic interference, etc. Customers are requested to observe applicable regulations and standards in the design of products.

· Fail-Safe Design

Any semiconductor devices have inherently a certain rate of failure. You must protect against injury, damage or loss from such failures by incorporating safety design measures into your facility and equipment such as redundancy, fire protection, and prevention of over-current levels and other abnormal operating conditions.

· Precautions Related to Usage of Devices

FUJITSU SEMICONDUCTOR semiconductor devices are intended for use in standard applications (computers, office automation and other office equipment, industrial, communications, and measurement equipment, personal or household devices, etc.).

CAUTION: Customers considering the use of our products in special applications where failure or abnormal operation may directly affect human lives or cause physical injury or property damage, or where extremely high levels of reliability are demanded (such as aerospace systems, atomic energy controls, sea floor repeaters, vehicle operating controls, medical devices for life support, etc.) are requested to consult with sales representatives before such use. The company will not be responsible for damages arising from such use without prior approval.

2. Precautions for Package Mounting

Package mounting may be either lead insertion type or surface mount type. In either case, for heat resistance during soldering, you should only mount under FUJITSU SEMICONDUCTOR's recommended conditions. For detailed information about mount conditions, contact your sales representative.

· Lead Insertion Type

Mounting of lead insertion type packages onto printed circuit boards may be done by two methods: direct soldering on the board, or mounting by using a socket.

Direct mounting onto boards normally involves processes for inserting leads into through-holes on the board and using the flow soldering (wave soldering) method of applying liquid solder. In this case, the soldering process usually causes leads to be subjected to thermal stress in excess of the absolute ratings for storage temperature. Mounting processes should conform to FUJITSU SEMICONDUCTOR recommended mounting conditions.

If socket mounting is used, differences in surface treatment of the socket contacts and IC lead surfaces can lead to contact deterioration after long periods. For this reason it is recommended that the surface treatment of socket contacts and IC leads be verified before mounting.

Surface Mount Type

Surface mount packaging has longer and thinner leads than lead-insertion packaging, and therefore leads are more easily deformed or bent. The use of packages with higher pin counts and narrower pin pitch results in increased susceptibility to open connections caused by deformed pins, or shorting due to solder bridges.

You must use appropriate mounting techniques. FUJITSU SEMICONDUCTOR recommends the solder reflow method, and has established a ranking of mounting conditions for each product. Users are advised to mount packages in accordance with FUJITSU SEMICONDUCTOR ranking of recommended conditions.

· Lead-Free Packaging

CAUTION: When ball grid array (BGA) packages with Sn-Ag-Cu balls are mounted using Sn-Pb eutectic soldering, junction strength may be reduced under some conditions of use.

· Storage of Semiconductor Devices

Because plastic chip packages are formed from plastic resins, exposure to natural environmental conditions will cause absorption of moisture. During mounting, the application of heat to a package that has absorbed moisture can cause surfaces to peel, reducing moisture resistance and causing packages to crack. To prevent, do the following:

- (1) Avoid exposure to rapid temperature changes, which cause moisture to condense inside the product. Store products in locations where temperature changes are slight.
- (2) Use dry boxes for product storage. Products should be stored below 70% relative humidity, and at temperatures between 5°C and 30°C.

 When you open Dry Package that recommends humidity 40% to 70% relative humidity.
- (3) When necessary, FUJITSU SEMICONDUCTOR packages semiconductor devices in highly moisture-resistant aluminum laminate bags, with a silica gel desiccant. Devices should be sealed in their aluminum laminate bags for storage.
- (4) Avoid storing packages where they are exposed to corrosive gases or high levels of dust.

Baking

Packages that have absorbed moisture may be de-moisturized by baking (heat drying). Follow the FUJITSU SEMICONDUCTOR recommended conditions for baking.

Condition: 125°C/24 h

· Static Electricity

Because semiconductor devices are particularly susceptible to damage by static electricity, you must take the following precautions:

- (1) Maintain relative humidity in the working environment between 40% and 70%. Use of an apparatus for ion generation may be needed to remove electricity.
- (2) Electrically ground all conveyors, solder vessels, soldering irons and peripheral equipment.
- (3) Eliminate static body electricity by the use of rings or bracelets connected to ground through high resistance (on the level of $1~\text{M}\Omega$). Wearing of conductive clothing and shoes, use of conductive floor mats and other measures to minimize shock loads is recommended.
- (4) Ground all fixtures and instruments, or protect with anti-static measures.
- (5) Avoid the use of styrofoam or other highly static-prone materials for storage of completed board assemblies.

3. Precautions for Use Environment

Reliability of semiconductor devices depends on ambient temperature and other conditions as described above.

For reliable performance, do the following:

(1) Humidity

Prolonged use in high humidity can lead to leakage in devices as well as printed circuit boards. If high humidity levels are anticipated, consider anti-humidity processing.

(2) Discharge of Static Electricity

When high-voltage charges exist close to semiconductor devices, discharges can cause abnormal operation. In such cases, use anti-static measures or processing to prevent discharges.

(3) Corrosive Gases, Dust, or Oil

Exposure to corrosive gases or contact with dust or oil may lead to chemical reactions that will adversely affect the device. If you use devices in such conditions, consider ways to prevent such exposure or to protect the devices.

(4) Radiation, Including Cosmic Radiation

Most devices are not designed for environments involving exposure to radiation or cosmic radiation. Users should provide shielding as appropriate.

(5) Smoke, Flame

CAUTION: Plastic molded devices are flammable, and therefore should not be used near combustible substances. If devices begin to smoke or burn, there is danger of the release of toxic gases. Customers considering the use of FUJITSU SEMICONDUCTOR products in other special environmental conditions should consult with sales representatives.

Please check the latest handling precautions at the following URL. http://edevice.fujitsu.com/fj/handling-e.pdf

■ HANDLING DEVICES

Power supply pins

In products with multiple VCC and VSS pins, respective pins at the same potential are interconnected within the device in order to prevent malfunctions such as latch-up. However, all of these pins should be connected externally to the power supply or ground lines in order to reduce electromagnetic emission levels, to prevent abnormal operation of strobe signals caused by the rise in the ground level, and to conform to the total output current rating.

Moreover, connect the current supply source with each Power supply pins and GND pins of this device at low impedance. It is also advisable that a ceramic capacitor of approximately $0.1~\mu F$ be connected as a bypass capacitor between each Power supply pins and GND pins near this device.

Crystal oscillator circuit

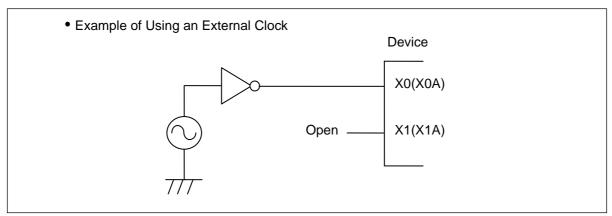
Noise near the X0/X1 and X0A/X1A pins may cause the device to malfunction. Design the printed circuit board so that X0/X1, X0A/X1A pins, the crystal oscillator (or ceramic oscillator), and the bypass capacitor to ground are located as close to the device as possible.

It is strongly recommended that the PC board artwork be designed such that the X0/X1 and X0A/X1A pins are surrounded by ground plane as this is expected to produce stable operation.

Using an external clock

bus system with power OFF.

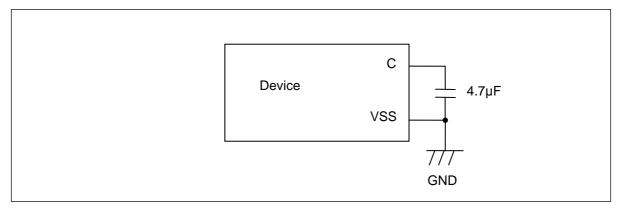
When using an external clock, the clock signal should be input to the X0, X0A pin only and the X1, X1A pin should be kept open.



Handling when using Multi-function serial pin as I²C pin If it is using Multi-function serial pin as I²C pins, P-ch transistor of digital output is always disable. However, I²C pins need to keep the electrical characteristic like other pins and not to connect to external I²C

C pin

As this series includes an internal regulator, always connect a bypass capacitor of approximately 4.7 µF to the C pin for use by the regulator.



Mode pins (MD0)

Connect the MD pin (MD0) directly to VCC or VSS pins. Design the printed circuit board such that the pull-up/down resistance stays low, as well as the distance between the mode pins and VCC pins or VSS pins is as short as possible and the connection impedance is low, when the pins are pulled-up/down such as for switching the pin level and rewriting the Flash memory data. It is because of preventing the device erroneously switching to test mode due to noise.

NC pins

NC pin should be kept open.

Notes on power-on

Turn power on/off in the following order or at the same time.

If not using the A/D converter, connect AVCC = VCC and AVSS = VSS.

Turning on :VCC → USBVCC

 $VCC \rightarrow AVCC \rightarrow AVRH$

Turning off: $USBVCC \rightarrow VCC$

 $AVRH \rightarrow AVCC \rightarrow VCC$

Serial Communication

There is a possibility to receive wrong data due to the noise or other causes on the serial communication. Therefore, design a printed circuit board so as to avoid noise.

Consider the case of receiving wrong data due to noise, perform error detection such as by applying a checksum of data at the end. If an error is detected, retransmit the data.

• Differences in features among the products with different memory sizes and between Flash products and MASK products

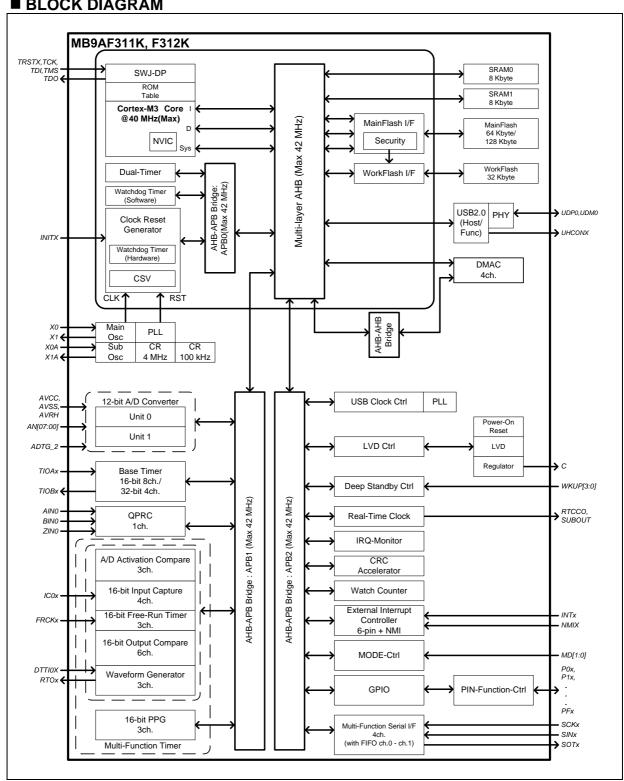
The electric characteristics including power consumption, ESD, latch-up, noise characteristics, and oscillation characteristics among the products with different memory sizes and between Flash products and MASK products are different because chip layout and memory structures are different.

If you are switching to use a different product of the same series, please make sure to evaluate the electric characteristics.

Pull-Up function of 5V tolerant I/O

Please do not input the signal more than VCC voltage at the time of Pull-Up function use of 5V tolerant I/O.

■ BLOCK DIAGRAM



■ MEMORY SIZE

See "●Memory size" in "■PRODUCT LINEUP" to confirm the memory size.

■ MEMORY MAP

			,	- 0x41FF_FFFF	Peripherals Area
					Reserved
	0xFFFF_FFFF] :	0x4006_1000	
		Reserved		0x4006_0000	DMAC
	0xE010_0000	Cortex-M3 Private		0x4005_0000	Reserved
	0xE000_0000	Peripherals	. ;	0x4004_0000	USB ch.0
				0x4003_C000	Reserved
		External Device	!	0x4003_B000	RTC
		Area		0x4003_A000	Watch Counter
		/ ιι σα	!	0x4003_9000	CRC
				0x4003_8000	MFS
	0x6000_0000		!	0x4003_7000	Reserved
	0.0000_0000		1 :	0x4003_6000	USB Clock Ctrl
		Reserved	i	0x4003_5000	LVD/DS mode
	0x4400_0000] ;	0x4003_4000	Reserved
		32Mbyte] ;	0x4003_3000	GPIO
	0x4200_0000	Bit band alias	_;	0x4003_2000	Reserved
		Dorinhorolo		0x4003_1000	Int-Req. Read
	0x4000_0000	Peripherals	ļ_	0x4003_0000	EXTI
				0x4002_F000	Reserved
		Reserved	1	0x4002_E000	CR Trim
	0x2400_0000	32Mbyte		0x4002_8000	Reserved
	0x2200_0000	Bit band alias	1	0x4002_7000	A/DC
	0x200E_1000	Reserved	;	0x4002_6000	QPRC
	0x200E_0000	WorkFlash I/F	\ \	0x4002_5000	Base Timer
	0x200C_0000	WorkFlash		0x4002_4000	PPG
	0x2008_0000	Reserved] }		
	0x2000_0000	SRAM1	<u> </u>		Reserved
See the next page	0x1FFF_0000	SRAM0	}	0x4002_1000	=
" Memory Map (2)" for		_] ;	0x4002_0000	MFT unit0
the memory size	0x0010_2000	Reserved	\	0x4001_6000	Reserved
details.	0x0010_0000	Security/CR Trim	į	0x4001_5000 0x4001_5000	Dual Timer
			1	0x4001_3000	Reserved
		MainFlash		0x4001_2000	SW WDT
	0.0000.000		1	0x4001_1000	HW WDT
	0x0000_0000]	0x4001_0000	Clock/Reset
			į	0x4000_1000	Reserved
			!	- 0x4000_0000	MainFlash I/F

Memory Map (2)

	MB9AF312K		MB9AF311K
0x200E_0000		0x200E_0000	
	Reserved		Reserved
0x200C_8000		0x200C_8000	
	WorkFlash		WorkFlash
0x200C_0000	32Kbyte	0x200C_0000	32Kbyte
	Reserved		Reserved
0x2000_2000		0x2000_2000	
	SRAM1		SRAM1
0x2000_0000	8Kbyte	0x2000_0000	8Kbyte
	SRAM0		SRAM0
0x1FFF_E000	8Kbyte	0x1FFF_E000	8Kbyte
0X1111 _L000		0.711 11	
	Reserved		Reserved
0x0010_2000 0x0010_1000	CR trimming	0x0010_2000 _ 0x0010_1000 _	CR trimming
0x0010_1000	Security	0x0010_1000 0x0010_0000	Security
_	į		
	Reserved		
			Reserved
0x0002_0000			
2 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2 2			
	MainFlash	0x0001_0000	
	128Kbyte		MainFlash
0x0000_0000		0x0000_0000	64Kbyte
0x0000_0000	12510910	0x0000_0000	

Peripheral Address Map

Peripheral Add	ress Map	1	T
Start address	End address	Bus	Peripherals
0x4000_0000	0x4000_0FFF	AHB	MainFlash I/F register
0x4000_1000	0x4000_FFFF	AIID	Reserved
0x4001_0000	0x4001_0FFF		Clock/Reset Control
0x4001_1000	0x4001_1FFF		Hardware Watchdog timer
0x4001_2000	0x4001_2FFF	APB0	Software Watchdog timer
0x4001_3000	0x4001_4FFF	Arbo	Reserved
0x4001_5000	0x4001_5FFF		Dual-Timer Dual-Timer
0x4001_6000	0x4001_FFFF		Reserved
0x4002_0000	0x4002_0FFF		Multi-function timer unit0
0x4002_1000	0x4002_3FFF		Reserved
0x4002_4000	0x4002_4FFF		PPG
0x4002_5000	0x4002_5FFF		Base Timer
0x4002_6000	0x4002_6FFF	APB1	Quadrature Position/Revolution Counter
0x4002_7000	0x4002_7FFF		A/D Converter
0x4002_8000	0x4002_DFFF		Reserved
0x4002_E000	0x4002_EFFF		Internal CR trimming
0x4002_F000	0x4002_FFFF		Reserved
0x4003_0000	0x4003_0FFF		External Interrupt Controller
0x4003_1000	0x4003_1FFF		Interrupt Request Batch-Read Function
0x4003_2000	0x4003_2FFF		Reserved
0x4003_3000	0x4003_3FFF		GPIO
0x4003_4000	0x4003_4FFF		Reserved
0x4003_5000	0x4003_57FF		Low-Voltage Detector
0x4003_5800	0x4003_5FFF	APB2	Deep stand-by mode Controller
0x4003_6000	0x4003_6FFF		USB clock generator
0x4003_7000	0x4003_7FFF		Reserved
0x4003_8000	0x4003_8FFF		Multi-function serial Interface
0x4003_9000	0x4003_9FFF		CRC
0x4003_A000	0x4003_AFFF		Watch Counter
0x4003_B000	0x4003_BFFF		Real-time clock
0x4003_C000	0x4003_FFFF		Reserved
0x4004_0000	0x4004_FFFF		USB ch.0
0x4005_0000	0x4005_FFFF		Reserved
0x4006_0000	0x4006_0FFF	AHB	DMAC register
0x4006_1000	0x41FF_FFFF		Reserved
0x200E_0000	0x200E_FFFF		WorkFlash I/F register

■ PIN STATUS IN EACH CPU STATE

The terms used for pin status have the following meanings.

• INITX=0

This is the period when the INITX pin is the "L" level.

• INITX=1

This is the period when the INITX pin is the "H" level.

•SPL=0

This is the status that standby pin level setting bit (SPL) in standby mode control register (STB_CTL) is set to "0".

• SPL=1

This is the status that standby pin level setting bit (SPL) in standby mode control register (STB_CTL) is set to "1".

· Input enabled

Indicates that the input function can be used.

• Internal input fixed at "0"

This is the status that the input function cannot be used. Internal input is fixed at "L".

· Hi-Z

Indicates that the output drive transistor is disabled and the pin is put in the Hi-Z state.

· Setting disabled

Indicates that the setting is disabled.

· Maintain previous state

Maintains the state that was immediately prior to entering the current mode. If a built-in peripheral function is operating, the output follows the peripheral function. If the pin is being used as a port, that output is maintained.

· Analog input is enabled

Indicates that the analog input is enabled.

· GPIO selected

In Deep stand-by mode, pins switch to the general-purpose I/O port.

List of Pin Status

_	List of Pin Sta	tus	ı	ı	ı	ı				1
Pin status type	Function group	group		Device internal reset state	Run mode or sleep mode state	_	mode, ode, or ode state	stand-by S	r Deep	Return from Deep stand-by mode state
Pin		Power supply unstable	-	oply stable	Power supply stable	'	oply stable	Power sup	. ,	Power supply stable INITX = 1
		-	INITX = 0	INITX = 1	INITX = 1	INITX = 1 SPL = 0 SPL = 1		SPL = 0	INITX = 1 SPL = 0 SPL = 1	
A	GPIO selected	Setting disabled	Setting disabled	Setting disabled	Maintain previous state	Maintain previous state	Hi-Z / Internal input fixed at "0"	Maintain previous state	Hi-Z / Internal input fixed at "0"	Maintain previous state
	Main crystal oscillator input pin	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled
	GPIO selected	Setting disabled	Setting disabled	Setting disabled	Maintain previous state	Maintain previous state	Hi-Z / Internal input fixed at "0"	Maintain previous state	Hi-Z / Internal input fixed at "0"	Maintain previous state
В	Main crystal oscillator output pin	Hi-Z/ Internal input fixed at "0"/ or Input enable	Hi-Z / Internal input fixed at "0"	Hi-Z / Internal input fixed at "0"	Maintain previous state	Maintain previous state /When oscillation stop* ¹ ,Hi-Z/ Internal input fixed at "0"	Maintain previous state /When oscillation stop* ¹ ,Hi-Z/ Internal input fixed at "0"	Maintain previous state /When oscillation stop*¹,Hi-Z/ Internal input fixed at "0"	Maintain previous state /When oscillation stop*¹,Hi-Z/ Internal input fixed at "0"	Maintain previous state /When oscillation stop*¹,Hi-Z// Internal input fixed at "0"
С	INITX input pin	Pull-up / Input enabled	Pull-up / Input enabled	Pull-up / Input enabled	Pull-up / Input enabled	Pull-up / Input enabled	Pull-up / Input enabled	Pull-up / Input enabled	Pull-up / Input enabled	Pull-up / Input enabled
D	Mode input pin	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled
	JTAG selected	Hi-Z	Pull-up / Input enabled	Pull-up / Input enabled	Maintain	Maintain	Maintain previous state	Maintain previous state	Maintain previous state	Maintain previous state
Е	GPIO selected	PIO Setting Setting state	previous state	previous state	Hi-Z / Internal input fixed at "0"	Maintain previous state	Hi-Z / Internal input fixed at "0"	Maintain previous state		

		1	I		I			I		
Pin status type	Function group	Power-on reset or low-voltage detection state	INITX input state	Device internal reset state	Run mode or sleep mode state		mode, lode, or lode state			Return from Deep stand-by mode state
Pin		Power supply unstable	Power sup	. ,	Power supply stable	Power supply stable		Power supply stable		Power supply stable
		-	INITX = 0	INITX = 1	INITX = 1	SPL = 0	X = 1 SPL = 1	SPL = 0	X = 1 SPL = 1	INITX = 1
	WKUP enabled	Setting disabled	Setting disabled	Setting disabled	Maintain previous state	Maintain previous state	Maintain previous state	WKUP input enabled	Hi-Z / WKUP input enabled	GPIO selected
F	Analog input selected	Hi-Z	Hi-Z / Internal input fixed at "0" / Analog input enabled	Hi-Z / Internal input fixed at "0" / Analog input enabled						
	External interrupt enabled selected Resource other than above selected	Setting disabled	Setting disabled	Setting disabled	Maintain previous state	Maintain previous state	Maintain previous state Hi-Z / Internal	GPIO selected	Hi-Z / Internal input fixed at "0"	GPIO selected
	GPIO selected						input fixed at "0"	Maintain previous state		Maintain previous state
	WKUP enabled	Setting disabled	Setting disabled	Setting disabled	Maintain previous state	Maintain previous state	Maintain previous state	WKUP input enabled	Hi-Z / WKUP input enabled	GPIO selected
G	External interrupt enabled selected	Setting disabled	Setting disabled	Setting disabled			Maintain previous state	GPIO	Hi-Z/	GPIO
	Resource other than above selected	Hi-Z	Hi-Z / Input	Hi-Z / Input	Maintain previous state	Maintain previous state	Hi-Z / Internal input fixed	selected Maintain	Internal input fixed at "0"	selected Maintain
	GPIO selected		enabled	enabled			at "0"	previous state		previous state
	External interrupt enabled selected	Setting disabled	Setting disabled	Setting disabled			Maintain previous state	GPIO	Hi-Z /	GPIO
Н	Resource other than above selected	Hi-Z	Hi-Z / Input	Hi-Z / Input	Maintain previous state	Maintain previous state	Hi-Z / Internal input fixed	selected Maintain	Internal input fixed at "0"	selected Maintain
	GPIO selected		enabled	enabled			at "0"	previous state		previous state
I	resource selected	Hi-Z	Hi-Z / Input	Hi-Z / Input	Maintain previous	Maintain previous	Hi-Z / Internal input fixed	GPIO selected Maintain	Hi-Z / Internal	GPIO selected Maintain
	GPIO selected		enabled	enabled	state	state	at "0"	previous state	input fixed at "0"	previous state

		-	ı					Ī		1
Pin status type	Function group	Power-on reset or low-voltage detection state	INITX input state	Device internal reset state	Run mode or sleep mode state	RTC m	mode, lode, or lode state	stand-by S	nd-by RTC or Deep TOP mode ate	Return from Deep stand-by mode state
Pin		Power supply unstable	Power sup	oply stable	Power supply stable	Power sup	oply stable	Power sup	oply stable	Power supply stable
		-	INITX = 0	INITX = 1	INITX = 1	SPL = 0	X = 1 SPL = 1	SPL = 0	X = 1 SPL = 1	INITX = 1
	NMIX selected	Setting disabled	Setting disabled	Setting disabled		0. 1	Maintain previous state	9. 2	Hi-Z /	GPIO
J	Resource other than above selected	Hi-Z	Hi-Z / Input	Hi-Z/ previous previous Hi-Z/ inp	WKUP input enabled	WKUP input enabled	selected Maintain			
	GPIO selected		enabled	enabled			at "0"			previous state
K	Analog input selected	Hi-Z	Hi-Z / Internal input fixed at "0" / Analog input enabled	Hi-Z / Internal input fixed at "0" / Analog input enabled	Hi-Z / Internal input fixed at "0" / Analog input enabled	Hi-Z / Internal input fixed at "0" / Analog input enabled	Hi-Z / Internal input fixed at "0" / Analog input enabled	Hi-Z / Internal input fixed at "0" / Analog input enabled	Hi-Z / Internal input fixed at "0" / Analog input enabled	Hi-Z / Internal input fixed at "0" / Analog input enabled
	Resource other than above selected	Setting	Setting	Setting	Maintain previous	Maintain previous	Hi-Z / Internal	GPIO selected	Hi-Z / Internal	GPIO selected
	GPIO selected	disabled	disabled	disabled	state	state	input fixed at "0"	Maintain previous state	at "0"	Maintain previous state
	Analog input selected	Hi-Z	Hi-Z / Internal input fixed at "0" / Analog input enabled	Hi-Z / Internal input fixed at "0" / Analog input enabled	Hi-Z / Internal input fixed at "0" / Analog input enabled	Hi-Z / Internal input fixed at "0" / Analog input enabled	Hi-Z / Internal input fixed at "0" / Analog input enabled	Hi-Z / Internal input fixed at "0" / Analog input enabled	Hi-Z / Internal input fixed at "0" / Analog input enabled	Hi-Z / Internal input fixed at "0" / Analog input enabled
L	External interrupt enabled selected Resource other than above selected	Setting disabled	Setting disabled	Setting disabled	Maintain previous state	Maintain previous state	Maintain previous state Hi-Z / Internal	GPIO selected	Hi-Z / Internal input fixed at "0"	GPIO selected
	GPIO selected						input fixed at "0"	Maintain previous state	at 0	Maintain previous state
	GPIO selected	Setting disabled	Setting disabled	Setting disabled	Maintain previous state	Maintain previous state	Hi-Z / Internal input fixed at "0"	Maintain previous state	Hi-Z / Internal input fixed at "0"	Maintain previous state
M	Sub crystal oscillator input pin	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled

Pin status type	Function group	Power-on reset or low-voltage detection state	INITX input state	Device internal reset state	Run mode or sleep mode state	RTC m	mode, ode, or ode state	mode of stand-by S	Deep stand-by RTC mode or Deep stand-by STOP mode state	
Pir		Power supply unstable	Power supply stable		Power supply stable	,	oply stable	Power supply stable		Power supply stable
		-	INITX = 0	INITX = 1	INITX = 1	SPL = 0	X = 1 SPL = 1	SPL = 0	SPL = 1	INITX = 1
	GPIO selected	Setting disabled	Setting disabled	Setting disabled	Maintain previous state	Maintain previous state	Hi-Z / Internal input fixed at "0"	Maintain previous state	Hi-Z / Internal input fixed at "0"	Maintain previous state
N	Sub crystal oscillator output pin	Hi-Z/ Internal input fixed at "0"/ or Input enable	Hi-Z / Internal input fixed at "0"	Hi-Z / Internal input fixed at "0"	Maintain previous state	Maintain previous state /When oscillation stop*²,Hi-Z/ Internal input fixed at "0"				
	GPIO selected	Hi-Z	Hi-Z / Input enabled	Hi-Z / Input enabled	Maintain previous state	Maintain previous state	Hi-Z / Internal input fixed at "0"	Maintain previous state	Hi-Z / Internal input fixed at "0"	Maintain previous state
0	USB I/O pin	Setting disabled	Setting disabled	Setting disabled	Maintain previous state	enabled/ Internal	Hi-Z at transmis- sion/ Input enabled/ Internal input fixed at "0" at reception	Hi-Z / Input enabled	Hi-Z / Input enabled	Hi-Z / Input enabled
	Mode input pin	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled	Input enabled
P	GPIO selected	Setting disabled	Setting disabled	Setting disabled	Maintain previous state	Maintain previous state	Hi-Z / Input enabled	Maintain previous state	Hi-Z / Input enabled	Maintain previous state

^{*1 :} Oscillation is stopped at Sub timer mode, Low-speed CR timer mode, RTC mode, STOP mode, Deep stand-by RTC mode, and Deep stand-by STOP mode.

^{*2 :} Oscillation is stopped at STOP mode and Deep stand-by STOP mode.

■ ELECTRICAL CHARACTERISTICS

1. Absolute Maximum Ratings

Doromotor	Cymbol	F	Rating	Lloit	Domorko
Parameter	Symbol	Min	Max	Unit	Remarks
Power supply voltage *1, *2	Vcc	Vss - 0.5	Vss + 6.5	V	
Power supply voltage (for USB) *1, *3	USBVcc	Vss - 0.5	Vss + 6.5	V	
Analog power supply voltage *1, *4	AVcc	Vss - 0.5	Vss + 6.5	V	
Analog reference voltage *1, *4	AVRH	Vss - 0.5	Vss + 6.5	V	
		Vss - 0.5	Vcc + 0.5 (≤6.5V)	V	Except for USB pin
Input voltage	$V_{\rm I}$	Vss - 0.5	USBVcc0 + 0.5 (≤6.5V)	V	USB pin
		Vss - 0.5	Vss + 6.5	V	5V tolerant
Analog pin input voltage	V_{IA}	Vss - 0.5	AVcc + 0.5 (≤6.5V)	V	
Output voltage	V_{O}	Vss - 0.5	Vcc + 0.5 (≤6.5V)	V	
"L" level maximum output current *5	I_{OL}		10	mA	4mA type
L level maximum output current	IOL		20	mA	12mA type
"L" level average output current *6	I_{OLAV}	_	4	mA	4mA type
L level average output current	IOLAV		12	mA	12mA type
"L" level total maximum output current	$\sum I_{OL}$		100	mA	
"L" level total average output current *7	$\sum I_{OLAV}$		50	mA	
"H" level maximum output current *5	T		- 10	mA	4mA type
11 level maximum output current	I_{OH}	-	- 20	mA	12mA type
"H" laval average output current *6	T		- 4	mA	4mA type
"H" level average output current *6	I_{OHAV}	=	- 12	mA	12mA type
"H" level total maximum output current	$\sum I_{\mathrm{OH}}$	-	- 100	mA	
"H" level total average output current *7	$\sum I_{OHAV}$	-	- 50	mA	
Power consumption	P_{D}	-	300	mW	
Storage temperature	T_{STG}	- 55	+ 150	°C	

^{*1 :} These parameters are based on the condition that $V_{SS} = AV_{SS} = 0.0V$.

<WARNING>

Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

^{*2}: Vcc must not drop below V_{SS} - 0.5V.

^{*3:} USBVcc must not drop below V_{SS} - 0.5V.

^{*4}: Ensure that the voltage does not to exceed Vcc + 0.5 V, for example, when the power is turned on.

^{*5:} The maximum output current is the peak value for a single pin.

^{*6:} The average output is the average current for a single pin over a period of 100 ms.

^{*7:} The total average output current is the average current for all pins over a period of 100 ms.

2. Recommended Operating Conditions

(Vss = AVss = 0.0V)

Parameter	Symbol	Conditions	V	alue	Unit	Remarks	
Faiametei	Symbol	Conditions	Min	Max	Offic	INGILIAINS	
Power supply voltage	Vcc	-	2.7	5.5	V		
Power supply voltage for USB	USBVcc	-	3.0	3.6 (≤Vcc)	V	*1	
Tower supply rollinge to 2002	002 100		2.7	5.5 (≤Vcc)	,	*2	
Analog power supply voltage	AVcc	-	2.7	5.5	V	AVcc=Vcc	
Analog reference voltage	AVRH	-	AVss	AVcc	V		
Operating temperature	Ta	-	- 40	+ 105	°C		

^{*1:} When P81/UDP0 and P80/UDM0 pin are used as USB (UDP0, UDM0).

<WARNING>

The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated within these ranges.

Always use semiconductor devices within their recommended operating condition ranges. Operation outside these ranges may adversely affect reliability and could result in device failure. No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their representatives beforehand.

^{*2:} When P81/UDP0 and P80/UDM0 pin are used as GPIO (P81, P80).

3. DC Characteristics

(1) Current Rating

 $(Vcc = AVcc = 2.7V \text{ to } 5.5V, USBVcc = 3.0V \text{ to } 3.6V, Vss = AVss = 0V, Ta = -40^{\circ}C \text{ to } + 105^{\circ}C)$

Б		Pin		- 3.0 V 10	Value	55 – AV		$Ta = -40^{\circ}C \text{ to } + 105^{\circ}C)$											
Parameter	Symbol	name	Conditions	Min	Тур	Max	Unit	Remarks											
			Normal operation	-	32	41	mA	CPU: 40MHz, Peripheral: 40MHz, MainFlash 0Wait FRWTR.RWT = 00 FSYNDN.SD = 000 *1											
			(PLL)	-	21	28	mA	CPU: 40MHz, Peripheral: 40MHz, MainFlash 3Wait FRWTR.RWT = 00 FSYNDN.SD = 011 *1											
	Ice	Icc												Normal operation (high-speed internal CR)	ı	3.9	7.7	mA	CPU/Peripheral : 4MHz *1, *2 MainFlash 0Wait FRWTR.RWT = 00 FSYNDN.SD = 000
							Normal operation (sub oscillation)	1	0.15	3.2	mA	CPU/Peripheral: 32kHz MainFlash 0Wait FRWTR.RWT = 00 FSYNDN.SD = 000 *1							
Power supply current			Normal operation (low-speed internal CR)	-	0.2	3.3	mA	CPU/Peripheral: 100kHz Flash 0Wait FRWTR.RWT = 00 FSYNDN.SD = 000 *1											
			SLEEP operation (PLL)	-	10	15	mA	Peripheral : 40MHz *1											
	Iccs		SLEEP operation (high-speed internal CR)	-	1.2	4.4	mA	Peripheral : 4MHz *1, *2											
	ices		SLEEP operation (sub oscillation)	-	0.1	3.1	mA	Peripheral : 32kHz *1											
										SLEEP operation (low-speed internal CR)	ı	0.1	3.1	mA	Peripheral : 100kHz *1				
	ī			STOP mode	1	35	200	μΑ	Ta = +25°C, When LVD is off *1										
	I_{CCH}		3101 mode	ı	-	3	mA	Ta = +105°C, When LVD is off *1											
	I _{CCT}	I _{CCT}	TIMER mode	-	60	230	μΑ	Ta = +25°C, When LVD is off *1											
			(sub oscillation)	-	-	3.1	mA	Ta = +105°C, When LVD is off *1											

Doromotor	Symbol	Pin	Conditions		Value		Unit	Remarks						
Parameter	Symbol	name	Conditions	Min	Тур	Max	Unit	Remarks						
	Ţ		DTCde	-	50	210	μΑ	Ta = +25°C, When LVD is off *1, *3						
	I_{CCR}		RTC mode	-	-	3.1	μΑ	Ta = +105°C, When LVD is off *1, *3						
											20	150	μΑ	Ta = + 25°C, When LVD is off RAM hold off *1, *4
	І _{ССНБ}		Deep stand-by	-	23	150	μΑ	Ta = + 25°C, When LVD is off RAM hold on *1, *4						
Power			STOP mode		-	600	μΑ	Ta = + 105°C, When LVD is off RAM hold off *1, *4						
Power supply current		VCC			ı	610	μΑ	Ta = + 105°C, When LVD is off RAM hold on *1, *4						
					30	160	μΑ	Ta = + 25°C, When LVD is off RAM hold off *1, *3, *4						
	Ţ		Deep stand-by	-	33	160	μΑ	Ta = +25°C, When LVD is off RAM hold on *1, *3, *4						
	I_{CCRD}		RTC mode					-	600	μΑ	Ta = + 105°C, When LVD is off RAM hold off *1, *3, *4			
				-	-	610	μΑ	Ta = + 105°C, When LVD is off RAM hold on *1, *3, *4						
Low-voltage detection circuit (LVD) power supply current	I _{CCLVD}		At operation	-	4	7	μΑ	For occurrence of interrupt						

^{*1:} When all ports are fixed.

^{*2:} When setting it to 4MHz by trimming.

^{*3:} When using sub crystal oscillator.

^{*4:} RAM hold setting is on-chip SRAM only.

(2) Pin Characteristics

 $(Vcc = AVcc = 2.7V \text{ to } 5.5V, Vss = AVss = 0V, Ta = -40^{\circ}C \text{ to } + 105^{\circ}C)$

Parameter	Symbol	Pin name	Conditions		Valu	· · · · · · · · · · · · · · · · · · ·		Remarks
Farameter	Symbol	Fill Hallie	Conditions	Min	Тур	Max	Offic	Nemains
"H" level input voltage	V _{IHS}	CMOS hysteresis input pin, MD0, MD1	-	Vcc × 0.8	-	Vcc + 0.3	V	
(hysteresis input)		5V tolerant input pin	-	$Vcc \times 0.8$	-	Vss + 5.5	V	
"L" level input voltage	V_{ILS}	CMOS hysteresis input pin, MD0, MD1	-	Vss - 0.3	-	Vcc × 0.2	v	
(hysteresis input)		5V tolerant input pin	-	Vss - 0.3	-	Vcc × 0.2	V	
		4mA type	$Vcc \ge 4.5 \text{ V}$ $I_{OH} = -4mA$ $Vcc < 4.5 \text{ V}$ $I_{OH} = -2mA$	Vcc - 0.5	1	Vcc	V	
"H" level output voltage	V_{OH}	12mA type	$Vcc \ge 4.5 \text{ V}$ $I_{OH} = -12\text{mA}$ $Vcc < 4.5 \text{ V}$ $I_{OH} = -8\text{mA}$	Vcc - 0.5	1	Vcc	V	
		The pin doubled as USB I/O	$\label{eq:USBVcc} \begin{split} &USBVcc \geq 4.5 \ V \\ &I_{OH} = \text{-} \ 20.5 \ \text{mA} \\ &USBVcc < 4.5 \ V \\ &I_{OH} = \text{-} \ 13.0 \ \text{mA} \end{split}$	USBVcc - 0.4	-	USBVcc	v	

Б.,		Pin	0 1:::		Value			Б
Parameter	Symbol	name	Conditions	Min	Тур	Max	Unit	Remarks
			$Vcc \ge 4.5 \text{ V}$					
		4mA type	$I_{OL} = 4mA$ $Vcc < 4.5 \text{ V}$	Vss	-	0.4	V	
			$I_{OL} = 2mA$					
"L" level output voltage	V _{OL}	12mA type	$Vcc \ge 4.5 \text{ V}$ $I_{OL} = 12\text{mA}$ $Vcc < 4.5 \text{ V}$ $I_{OL} = 8\text{mA}$	Vss	-	0.4	V	
		The pin doubled as USB I/O	$\begin{split} &I_{OL} = 8\text{mA} \\ &USBVcc \geq 4.5 \text{ V} \\ &I_{OL} = 18.5\text{mA} \\ &USBVcc < 4.5 \text{ V} \\ &I_{OL} = 10.5\text{mA} \end{split}$	Vss	-	0.4	V	
Input leak current	${ m I}_{ m IL}$	-	-	- 5	-	+ 5	μА	
Pull-up	_		Vcc ≥ 4.5 V	25	50	100		
resistance value	$R_{ m PU}$	Pull-up pin	Vcc < 4.5 V	30	80	200	kΩ	
Input capacitance	C _{IN}	Other than VCC, USBVCC, VSS, AVCC, AVSS, AVRH	-	-	5	15	pF	

4. AC Characteristics

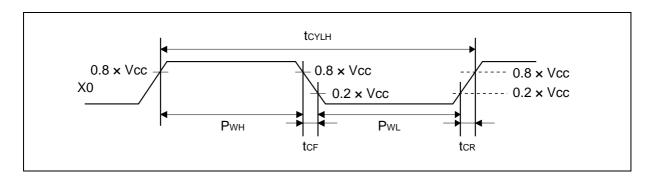
(1) Main Clock Input Characteristics

 $(Vcc = 2.7V \text{ to } 5.5V, Vss = 0V, Ta = -40^{\circ}C \text{ to } +105^{\circ}C)$

Parameter	Symbol	Pin	Conditions	Va	lue	Unit	Remarks	
Farameter	Symbol	name	Conditions	Min	Max	Offic	Nemarks	
			$Vcc \ge 4.5V$	4	48	MHz	When crystal oscillator	
Input frequency	F_{CH}		Vcc < 4.5V	4	20	WILLS	is connected	
input frequency	1 CH			$Vcc \ge 4.5V$	4	48	MHz	When using external
			Vcc < 4.5V	4	20	WILIZ	clock	
Input clock cycle	torry	X0	$Vcc \ge 4.5V$	20.83	250	ns	When using external	
input clock cycle	t _{CYLH}	X1	Vcc < 4.5V	50	250	113	clock	
Input clock pulse	_		Pwh/tcylh	45	55	%	When using external	
width	_		Pwl/tcylh	T-3	33	70	clock	
Input clock rise	$t_{CF,}$		_	_	5	ns	When using external	
time and fall time	t_{CR}				3	113	clock	
	F _{CC}	_	_	_	42	MHz	Base clock	
Internal operating	1 00				72	WILL	(HCLK/FCLK)	
clock frequency*1	F_{CP0}	-	-	-	42	MHz	APB0 bus clock*2	
clock frequency	F_{CP1}	-	-	-	42	MHz	APB1 bus clock* ²	
	F_{CP2}	-	-	-	42	MHz	APB2 bus clock* ²	
	4			22.0			Base clock	
T . 1	t _{CYCC}	ı	-	23.8	-	ns	(HCLK/FCLK)	
Internal operating clock cycle time*1	t_{CYCP0}	-	-	23.8	-	ns	APB0 bus clock*2	
	t_{CYCP1}	-	-	23.8	-	ns	APB1 bus clock*2	
	t_{CYCP2}	-	-	23.8	-	ns	APB2 bus clock* ²	

^{*1:} For more information about each internal operating clock, see "Chapter: Clock" in "FM3 Family PERIPHERAL MANUAL".

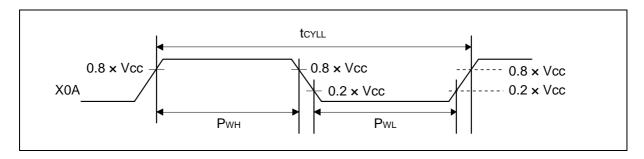
^{*2:} For about each APB bus which each peripheral is connected to, see "■ BLOCK DIAGRAM" in this data sheet.



(2) Sub Clock Input Characteristics

 $(Vcc = 2.7V \text{ to } 5.5V, Vss = 0V, Ta = -40^{\circ}C \text{ to } + 105^{\circ}C)$

				(.,	,		
Parameter	Symbol	Pin	Conditions		Value		Unit	Remarks	
Farameter	Symbol	name	Conditions	Min	Тур	Max	Offic	Remarks	
Input frequency	1/ t _{CYLL}		-	-	32.768	-	kHz	When crystal oscillator is connected	
		X0A	-	32	-	100	kHz	When using external clock	
Input clock cycle	t _{CYLL}	X1A	-	10	-	31.25	μs	When using external clock	
Input clock pulse width	-		Pwh/tcyll Pwl/tcyll	45	-	55	%	When using external clock	



(3) Internal CR Oscillation Characteristics

• High-speed Internal CR

 $(Vcc = 2.7V \text{ to } 5.5V, Vss = 0V, Ta = -40^{\circ}C \text{ to } + 105^{\circ}C)$

Parameter	Symbol	Conditions		Value		Unit	Remarks	
Farameter	Symbol	Conditions	Min	Тур	Max	Offic	Nemarks	
Clock frequency F _{CRH}		Ta = +25°C		4	4.04			
	Fany	$Ta = 0^{\circ}C \text{ to } + 70^{\circ}C$	3.84	4	4.16	MHz	When trimming*	
	1 CRH	$Ta = -40^{\circ}C \text{ to} + 85^{\circ}C$	3.8	4	4.2	IVIIIZ		
		$Ta = -40^{\circ}C \text{ to} + 85^{\circ}C$	3	4	5		When not trimming	

^{*:} In the case of using the values in CR trimming area of Flash memory at shipment for frequency trimming.

· Low-speed Internal CR

 $(Vcc = 2.7V \text{ to } 5.5V, Vss = 0V, Ta = -40^{\circ}C \text{ to } + 105^{\circ}C)$

Parameter	Symbol	Conditions		Value		Unit	Domorko
	Symbol	Conditions	Min	Тур	Max	Offic	Remarks
Clock frequency	F _{CRL}	-	50	100	150	kHz	

(4-1) Operating Conditions of Main and USB PLL (In the case of using main clock for input of PLL)

 $(Vcc = 2.7V \text{ to } 5.5V, Vss = 0V, Ta = -40^{\circ}C \text{ to } + 105^{\circ}C)$

Parameter	Symbol	Value			Unit	Remarks
Farameter	Symbol	Min	Тур	Max	Offic	Remarks
PLL oscillation stabilization wait time* (LOCK UP time)	t _{LOCK}	100	ı	-	μs	
PLL input clock frequency	F_{PLLI}	4	-	16	MHz	
PLL multiple rate	-	13	-	75	multiple	
PLL macro oscillation clock frequency	F_{PLLO}	200	-	300	MHz	

^{*:} Time from when the PLL starts operating until the oscillation stabilizes.

(4-2) Operating Conditions of Main PLL (In the case of using high-speed internal CR)

 $(Vcc = 2.7V \text{ to } 5.5V, Vss = 0V, Ta = -40^{\circ}C \text{ to } +105^{\circ}C)$

Parameter	Symbol	Value			Unit	Remarks
raiailletei	Symbol	Min	Тур	Max	Offic	Remarks
PLL oscillation stabilization wait time* (LOCK UP time)	t _{LOCK}	100	ı	-	μs	
PLL input clock frequency	F_{PLLI}	3.8	4	4.2	MHz	
PLL multiple rate	-	50	1	71	multiple	
PLL macro oscillation clock frequency	F_{PLLO}	190	1	300	MHz	

^{*:} Time from when the PLL starts operating until the oscillation stabilizes.

Note: It needs to input to PLL by internal CR trimming frequency.

(5) Reset Input Characteristics

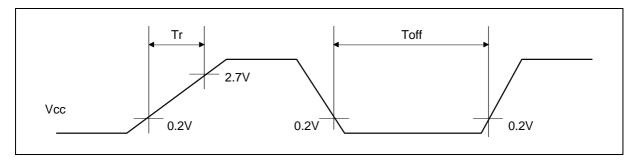
 $(Vcc = 2.7V \text{ to } 5.5V, Vss = 0V, Ta = -40^{\circ}C \text{ to } + 105^{\circ}C)$

Parameter	Symbol	Pin	Conditions	Va	lue	Unit	Remarks
	Symbol	name	Conditions	Min	Max	Offic	
Reset input time	t _{INITX}	INITX	-	500	-	ns	

(6) Power-on Reset Timing

 $(Vcc = 2.7V \text{ to } 5.5V, Vss = 0V, Ta = -40^{\circ}C \text{ to } +105^{\circ}C)$

Doromotor	Symbol	Pin	Val	ue	Unit	Domarko		
Parameter	Symbol	name	Min	Max	Offic	Remarks		
Power supply rising time	Tr	VCC	0	-	ms			
Power supply shut down time	Toff	VCC	1	-	ms			

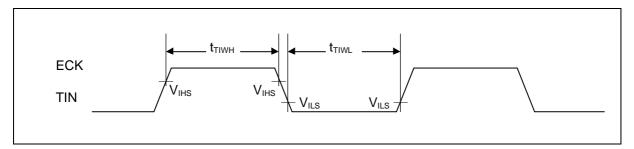


(7) Base Timer Input Timing

· Timer input timing

 $(Vcc = 2.7V \text{ to } 5.5V, Vss = 0V, Ta = -40^{\circ}C \text{ to } +105^{\circ}C)$

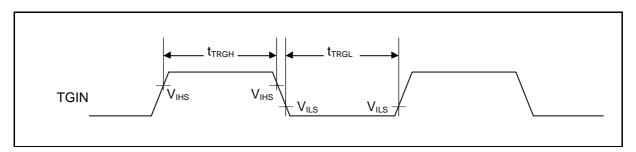
Parameter	Symbol Pin name		Conditions	Val	ue	Linit	Remarks	
Farameter	Syllibol	FIII Hallie	Conditions	Min	Max	Offic	INGIIIAINS	
Input pulse width	t _{TIWH} t _{TIWL}	TIOAn/TIOBn (when using as ECK, TIN)	-	2t _{CYCP}	-	ns		



· Trigger input timing

 $(Vcc = 2.7V \text{ to } 5.5V, Vss = 0V, Ta = -40^{\circ}C \text{ to } +105^{\circ}C)$

				,				
Doromotor	Symbol	Pin name	Conditions	Val	ue	Unit	Remarks	
Parameter	Symbol	Finnanie	Conditions	Min	Max	Offic	Remarks	
Input pulse width	t _{TRGH} t _{TRGL}	TIOAn/TIOBn (when using as TGIN)	-	2t _{CYCP}	-	ns		



Note: t_{CYCP} indicates the APB bus clock cycle time.

About the APB bus number which UART is connected to, see "■BLOCK DIAGRAM" in this data sheet.

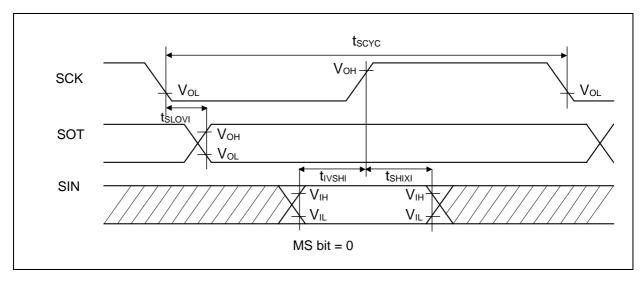
(8) UART Timing

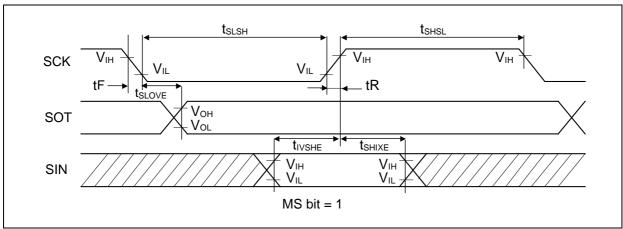
• Synchronous serial (SPI = 0, SCINV = 0)

 $(Vcc = 2.7V \text{ to } 5.5V, Vss = 0V, Ta = -40^{\circ}C \text{ to } +105^{\circ}C)$

Doromotor	Symbol	Pin	Conditions	Vcc <	4.5V	Vcc ≥	Unit	
Parameter	Symbol	name	Conditions	Min	Max	Min	Max	Offic
Serial clock cycle time	t _{SCYC}	SCKx		4tcycp	ı	4tcycp	1	ns
$SCK \downarrow \rightarrow SOT$ delay time	t _{SLOVI}	SCKx SOTx	Internal shift	-30	+30	- 20	+ 20	ns
$SIN \rightarrow SCK \uparrow setup time$	t _{IVSHI}	SCKx SINx	clock operation	50	1	30	ī	ns
$SCK \uparrow \rightarrow SIN \text{ hold time}$	t_{SHIXI}	SCKx SINx		0	-	0	-	ns
Serial clock "L" pulse width	t _{SLSH}	SCKx		2tcycp - 10	1	2tcycp - 10	ī	ns
Serial clock "H" pulse width	t _{SHSL}	SCKx		tcycp + 10	1	tcycp + 10	ı	ns
$SCK \downarrow \rightarrow SOT$ delay time	t_{SLOVE}	SCKx SOTx	External shift	ı	50	-	30	ns
$SIN \rightarrow SCK \uparrow setup time$	t _{IVSHE}	SCKx SINx	clock operation	10	1	10	ı	ns
$SCK \uparrow \rightarrow SIN \text{ hold time}$	t _{SHIXE}	SCKx SINx		20	-	20	-	ns
SCK fall time	tF	SCKx		-	5	-	5	ns
SCK rise time	tR	SCKx		-	5	-	5	ns

- Notes: The above characteristics apply to CLK synchronous mode.
 - $t_{\mbox{\scriptsize CYCP}}$ indicates the APB bus clock cycle time. About the APB bus number which UART is connected to, see "BLOCK DIAGRAM" in this data
 - These characteristics only guarantee the same relocate port number. For example, the combination of SCLKx_0 and SOTx_1 is not guaranteed.
 - When the external load capacitance = 30pF.





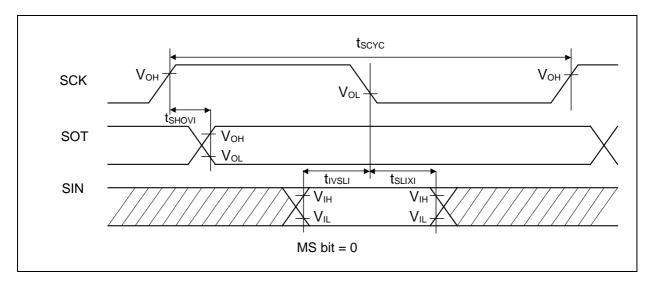
• Synchronous serial (SPI = 0, SCINV = 1)

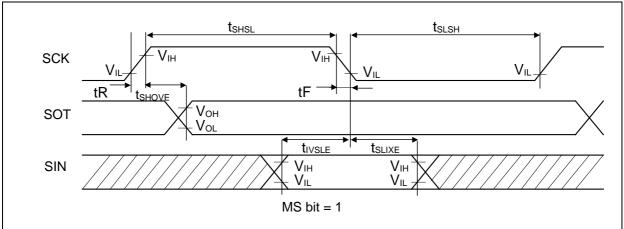
 $(Vcc = 2.7V \text{ to } 5.5V, Vss = 0V, Ta = -40^{\circ}C \text{ to } + 105^{\circ}C)$

Parameter	Symbol	Pin	Conditions	Vcc < 4	4.5V	Vcc≥	4.5V	Unit
Parameter	Symbol	name	Conditions	Min	Max	Min	Max	Offic
Serial clock cycle time	t_{SCYC}	SCKx		4tcycp	-	4tcycp	-	ns
$SCK \uparrow \rightarrow SOT$ delay time	t _{SHOVI}	SCKx SOTx	Internal shift clock operation	-30	+30	- 20	+ 20	ns
$SIN \rightarrow SCK \downarrow setup time$	t _{IVSLI}	SCKx SINx		50	-	30	-	ns
$SCK \downarrow \rightarrow SIN \text{ hold time}$	t _{SLIXI}	SCKx SINx		0	-	0	ī	ns
Serial clock "L" pulse width	t _{SLSH}	SCKx		2tcycp - 10	-	2tcycp - 10	ı	ns
Serial clock "H" pulse width	t_{SHSL}	SCKx		tcycp + 10	-	tcycp + 10	-	ns
$SCK \uparrow \rightarrow SOT$ delay time	t _{SHOVE}	SCKx SOTx	External shift clock	-	50	-	30	ns
$SIN \rightarrow SCK \downarrow setup time$	t _{IVSLE}	SCKx SINx	operation	10	-	10	-	ns
$SCK \downarrow \rightarrow SIN \text{ hold time}$	t _{SLIXE}	SCKx SINx		20	-	20	1	ns
SCK fall time	tF	SCKx		-	5	-	5	ns
SCK rise time	tR	SCKx		-	5	-	5	ns

Notes: • The above characteristics apply to CLK synchronous mode.

- t_{CYCP} indicates the APB bus clock cycle time.
 About the APB bus number which UART is connected to, see "■BLOCK DIAGRAM" in this data sheet.
- These characteristics only guarantee the same relocate port number. For example, the combination of SCLKx_0 and SOTx_1 is not guaranteed.
- When the external load capacitance = 30pF.





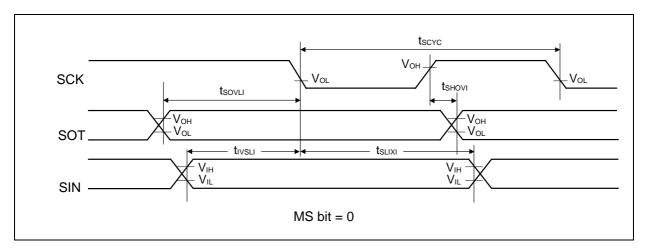
• Synchronous serial (SPI = 1, SCINV = 0)

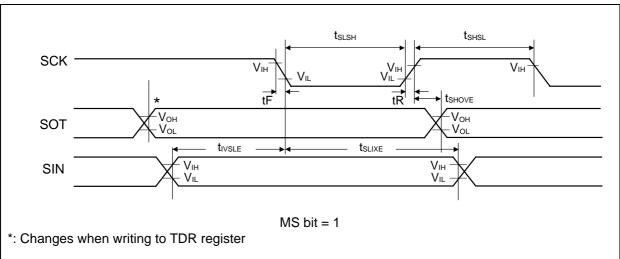
 $(Vcc = 2.7V \text{ to } 5.5V, Vss = 0V, Ta = -40^{\circ}C \text{ to } + 105^{\circ}C)$

Parameter	Symbol	Pin	Conditions	Vcc < 4	4.5V	Vcc≥	4.5V	Unit
Parameter	Symbol	name	Conditions	Min	Max	Min	Max	Offic
Serial clock cycle time	t_{SCYC}	SCKx		4tcycp	-	4tcycp	ı	ns
$SCK \uparrow \rightarrow SOT$ delay time	t _{SHOVI}	SCKx SOTx		-30	+30	- 20	+ 20	ns
$SIN \rightarrow SCK \downarrow setup time$	t _{IVSLI}	SCKx SINx	Internal shift clock operation	50	-	30	1	ns
$SCK \downarrow \rightarrow SIN \text{ hold time}$	t _{SLIXI}	SCKx SINx		0	-	0	1	ns
$SOT \rightarrow SCK \downarrow delay time$	t _{SOVLI}	SCKx SOTx		2tcycp - 30	-	2tcycp - 30	-	ns
Serial clock "L" pulse width	t _{SLSH}	SCKx		2tcycp - 10	-	2tcycp - 10	ı	ns
Serial clock "H" pulse width	t _{SHSL}	SCKx		tcycp + 10	-	tcycp + 10	-	ns
$SCK \uparrow \rightarrow SOT$ delay time	t _{SHOVE}	SCKx SOTx	External shift clock	-	50	-	30	ns
$SIN \rightarrow SCK \downarrow setup time$	t _{IVSLE}	SCKx SINx	operation	10	-	10	ı	ns
$SCK \downarrow \rightarrow SIN \text{ hold time}$	t _{SLIXE}	SCKx SINx		20	-	20	-	ns
SCK fall time	tF	SCKx		-	5	-	5	ns
SCK rise time	tR	SCKx		-	5	-	5	ns

Notes: • The above characteristics apply to CLK synchronous mode.

- t_{CYCP} indicates the APB bus clock cycle time.
 About the APB bus number which UART is connected to, see "■BLOCK DIAGRAM" in this data sheet.
- These characteristics only guarantee the same relocate port number. For example, the combination of SCLKx_0 and SOTx_1 is not guaranteed.
- When the external load capacitance = 30pF.





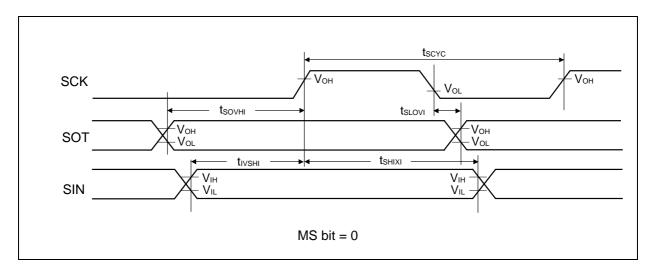
• Synchronous serial (SPI = 1, SCINV = 1)

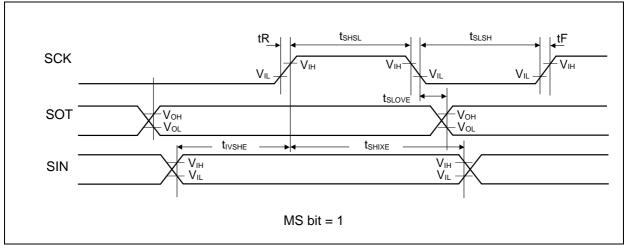
 $(Vcc = 2.7V \text{ to } 5.5V, Vss = 0V, Ta = -40^{\circ}C \text{ to } +105^{\circ}C)$

Parameter	Symbol	Pin	Conditions	Vcc < 4	4.5V	Vcc≥	4.5V	Unit
Parameter	Symbol	name	Conditions	Min	Max	Min	Max	Ullit
Serial clock cycle time	t _{SCYC}	SCKx		4tcycp	-	4tcycp	-	ns
$SCK \downarrow \rightarrow SOT$ delay time	$t_{ m SLOVI}$	SCKx SOTx		-30	+30	- 20	+ 20	ns
$SIN \rightarrow SCK \uparrow setup time$	t _{IVSHI}	SCKx SINx	Internal shift clock	50	-	30	-	ns
$SCK \uparrow \rightarrow SIN \text{ hold time}$	t_{SHIXI}	SCKx SINx	operation	0	-	0	1	ns
$SOT \rightarrow SCK \uparrow delay time$	t _{SOVHI}	SCKx SOTx		2tcycp - 30	-	2tcycp - 30	-	ns
Serial clock "L" pulse width	t _{SLSH}	SCKx		2tcycp - 10	-	2tcycp - 10	1	ns
Serial clock "H" pulse width	t _{SHSL}	SCKx		tcycp + 10	-	tcycp + 10	1	ns
$SCK \downarrow \rightarrow SOT$ delay time	t_{SLOVE}	SCKx SOTx	External shift clock	-	50	-	30	ns
$SIN \rightarrow SCK \uparrow setup time$	t_{IVSHE}	SCKx SINx	operation	10	-	10	-	ns
$SCK \uparrow \rightarrow SIN \text{ hold time}$	t _{SHIXE}	SCKx SINx		20	-	20	-	ns
SCK fall time	tF	SCKx		-	5	-	5	ns
SCK rise time	tR	SCKx		-	5	-	5	ns

Notes: • The above characteristics apply to CLK synchronous mode.

- t_{CYCP} indicates the APB bus clock cycle time.
 About the APB bus number which UART is connected to, see "■BLOCK DIAGRAM" in this data sheet.
- These characteristics only guarantee the same relocate port number. For example, the combination of SCLKx_0 and SOTx_1 is not guaranteed.
- When the external load capacitance = 30pF.

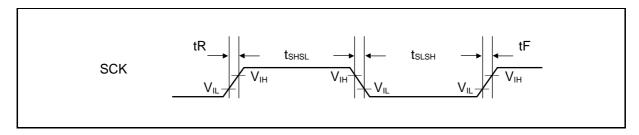




• External clock (EXT = 1): asynchronous only

 $(Vcc = 2.7V \text{ to } 5.5V, Vss = 0V, Ta = -40^{\circ}C \text{ to } +105^{\circ}C)$

Parameter	Symbol	Conditions	Min	Max	Unit	Remarks
Serial clock "L" pulse width	t _{SLSH}		tcycp + 10	-	ns	
Serial clock "H" pulse width	t_{SHSL}	$C_L = 30pF$	tcycp + 10	-	ns	
SCK fall time	tF	C _L = 30pr	-	5	ns	
SCK rise time	tR		-	5	ns	



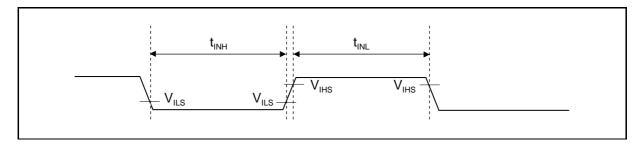
(9) External Input Timing

 $(Vcc = 2.7V \text{ to } 5.5V, Vss = 0V, Ta = -40^{\circ}C \text{ to } + 105^{\circ}C)$

Parameter	Symbol	Pin name	Conditions	Value		Unit	Remarks	
raiaillelei	Symbol	Fill Hallie	Conditions	Min	Max) ii	Remarks	
		ADTG					A/D converter	
		ADIO		2t _{CYCP} *1			trigger input	
		FRCKx	-		-	ns	Free-run timer input	
		TRCKX					clock	
	.	ICxx					Input capture	
Input pulse width	t _{INH,}	DTTIxX		2t _{CYCP} *1		ne	Wave form	
	t _{INL}	DITIXA	-	ZiCYCP.	-	ns	generator	
		INT00 to INT15	-	$2t_{CYCP} + 100*^1$	-	ns	External interrupt	
		NMIX		500* ²	-	ns	NMI	
		WKUPx		820*3		ne	Deep stand-by wake	
		WKUPX	-	820*	-	ns	up	

^{*1 :} t_{CYCP} indicates the APB bus clock cycle time except stop when in stop mode, in rtc mode, in timer mode. About the APB bus number which A/D converter, Multi-function Timer, External interrupt are connected to, see "■BLOCK DIAGRAM" in this data sheet.

^{*3 :} When in deep stand-by stop mode, in deep stand-by rtc mode.



^{*2 :} When in stop mode, in rtc mode, in timer mode.

(10) Quadrature Position/Revolution Counter timing

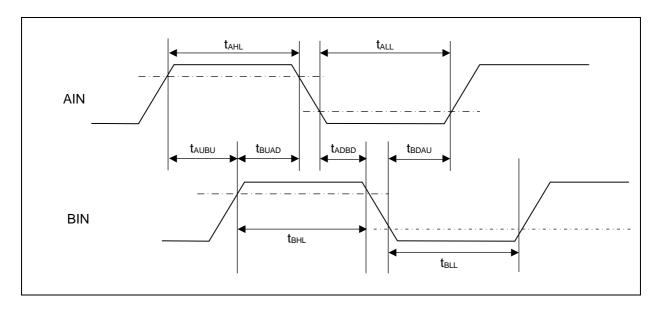
 $(Vcc = 2.7V \text{ to } 5.5V, Vss = 0V, Ta = -40^{\circ}C \text{ to } + 105^{\circ}C)$

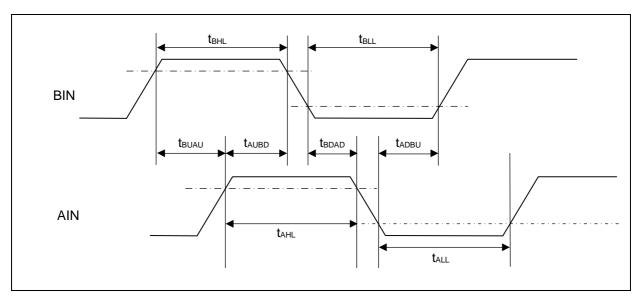
Parameter	Symbol	`	$\frac{\text{V to 3.3 V, V ss} = 0}{\text{Val}}$	•	
Parameter	Symbol	Conditions	Min	Max	Unit
AIN pin "H" width	$t_{ m AHL}$	-			
AIN pin "L" width	$t_{ m ALL}$	-			
BIN pin "H" width	$t_{ m BHL}$	=			
BIN pin "L" width	$t_{ m BLL}$	=			
BIN rise time from		PC_Mode2 or			
AIN pin "H" level	t_{AUBU}	PC_Mode3			
AIN fall time from	+	PC_Mode2 or			
BIN pin "H" level	$t_{ m BUAD}$	PC_Mode3			
BIN fall time from	+	PC_Mode2 or			
AIN pin "L" level	$t_{ m ADBD}$	PC_Mode3			
AIN rise time from	+	PC_Mode2 or			
BIN pin "L" level	$t_{ m BDAU}$	PC_Mode3			ns
AIN rise time from	+	PC_Mode2 or	2t _{CYCP} *		
BIN pin "H" level	$t_{ m BUAU}$	PC_Mode3	ZICYCP	-	
BIN fall time from	+	PC_Mode2 or			
AIN pin "H" level	t_{AUBD}	PC_Mode3			
AIN fall time from	+	PC_Mode2 or			
BIN pin "L" level	$t_{ m BDAD}$	PC_Mode3			
BIN rise time from	+	PC_Mode2 or			
AIN pin "L" level	$t_{ m ADBU}$	PC_Mode3			
ZIN pin "H" width	t_{ZHL}	QCR:CGSC="0"			
ZIN pin "L" width	t_{ZLL}	QCR:CGSC="0"			
AIN/BIN rise and fall time	f .	QCR:CGSC="1"			
from determined ZIN level	t _{ZABE}	VCN.COSC- 1			
Determined ZIN level from	t. ppg	QCR:CGSC="1"			
AIN/BIN rise and fall time	t_{ABEZ}				

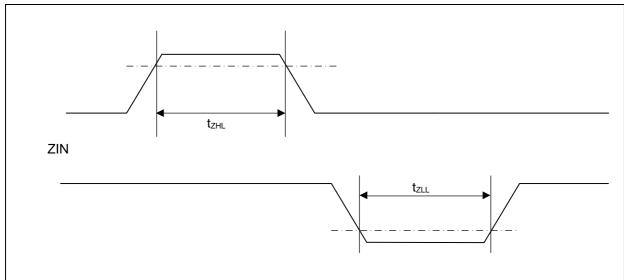
^{*:} t_{CYCP} indicates the APB bus clock cycle time except stop when in stop mode, in timer mode.

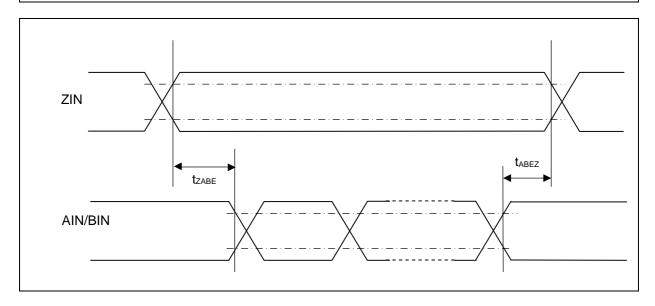
About the APB bus number which Quadrature Position/Revolution Counter is connected to, see "

BLOCK DIAGRAM" in this data sheet.









(11) I²C Timing

 $(Vcc = 2.7V \text{ to } 5.5V, Vss = 0V, Ta = -40^{\circ}C \text{ to } + 105^{\circ}C)$

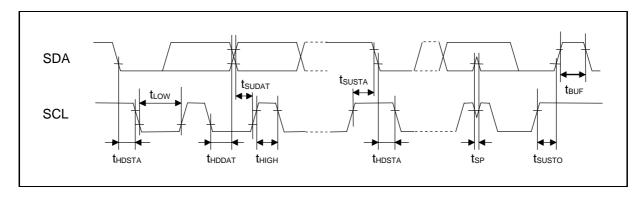
Parameter	Symbol	Conditions	Typical	mode	High-sp mod		Unit	Remarks
			Min	Max	Min	Max		
SCL clock frequency	F_{SCL}		0	100	0	400	kHz	
(Repeated) START condition								
hold time	t_{HDSTA}		4.0	-	0.6	-	μs	
$SDA \downarrow \rightarrow SCL \downarrow$								
SCLclock "L" width	t_{LOW}		4.7	-	1.3	-	μs	
SCLclock "H" width	t_{HIGH}		4.0	-	0.6	-	μs	
(Repeated) START setup time $SCL \uparrow \rightarrow SDA \downarrow$	t_{SUSTA}	C = 20pE	4.7	-	0.6	ı	μs	
Data hold time $SCL \downarrow \rightarrow SDA \downarrow \uparrow$	t _{HDDAT}	$C_L = 30pF,$ $R = (Vp/I_{OL})^{*1}$	0	3.45* ²	0	0.9*3	μs	
Data setup time $SDA \downarrow \uparrow \rightarrow SCL \uparrow$	t _{SUDAT}		250	-	100	1	ns	
STOP condition setup time $SCL \uparrow \rightarrow SDA \uparrow$	t _{SUSTO}		4.0	-	0.6	-	μs	
Bus free time between "STOP condition" and "START condition"	t _{BUF}		4.7	-	1.3	-	μs	
Noise filter	t_{SP}	-	$2 t_{CYCP}^{*4}$	-	$2 t_{CYCP}^{*4}$	-	ns	

^{*1 :} R and C represent the pull-up resistance and load capacitance of the SCL and SDA lines, respectively. Vp indicates the power supply voltage of the pull-up resistance and I_{OL} indicates V_{OL} guaranteed current.

^{*4:} t_{CYCP} is the APB bus clock cycle time.

About the APB bus number that I²C is connected to, see "■BLOCK DIAGRAM" in this data sheet.

To use I²C, set the peripheral bus clock at 8 MHz or more.



 $^{*2:} The \ maximum \ t_{HDDAT} \ must \ satisfy \ that \ it \ does \ not \ extend \ at \ least \ "L" \ period \ (t_{LOW}) \ of \ device's \ SCL \ signal.$

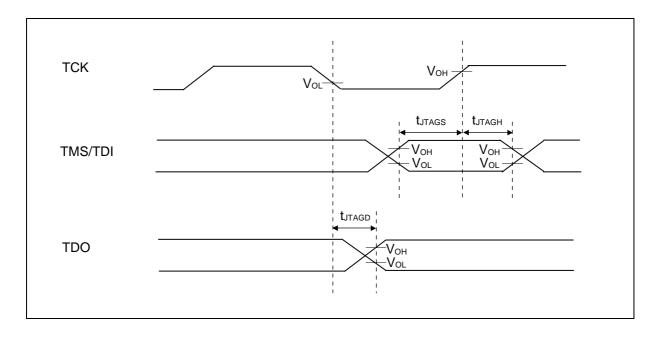
^{*3 :} A high-speed mode I^2C bus device can be used on a standard mode I^2C bus system as long as the device satisfies the requirement of " $t_{SUDAT} \ge 250$ ns".

(12) JTAG Timing

 $(Vcc = 2.7V \text{ to } 5.5V, Vss = 0V, Ta = -40^{\circ}C \text{ to } + 105^{\circ}C)$

Parameter	Symbol	Pin name	Conditions	Va	alue	Unit	Remarks
Farameter	Symbol	Fill Hallie	Conditions	Min	Max	Offic	Remarks
TMS, TDI setup	t	TCK,	$Vcc \ge 4.5V$	15		ns	
time	t_{JTAGS}	TMS, TDI	Vcc < 4.5V	13	ı	115	
TMS, TDI hold time	· ·	TCK,	$Vcc \ge 4.5V$	15		nc	
TWIS, TDI HOIG TIME	t _{JTAGH}	TMS, TDI	Vcc < 4.5V	13	-	ns	
TDO delevitime		TCK,	$Vcc \ge 4.5V$	-	25	na	
TDO delay time	t _{JTAGD}	TDO	Vcc < 4.5V	-	45	ns	

Note: When the external load capacitance = 30pF.



5. 12-bit A/D Converter

· Electrical characteristics for the A/D converter

 $(Vcc = AVcc = 2.7V \text{ to } 5.5V, Vss = AVss = 0V, Ta = -40^{\circ}C \text{ to } + 105^{\circ}C)$

Doromotor	Pin		Value	,	1 1 1 1 1 1	Domonico
Parameter	name	Min	Тур	Max	Unit	Remarks
Resolution	-	-	-	12	bit	
Linearity error	ı	- 4.5	-	+ 4.5	LSB	
Differential linearity error	-	-2.5	-	+ 2.5	LSB	
Zero transition voltage	AN0 to AN7	- 20	-	+ 20	mV	AVRH = 2.7V to 5.5V
Full-scale transition voltage	AN0 to AN7	AVRH - 20	-	AVRH + 20	mV	
Conversion time	ı	$1.0*^{1}$	-	-	μs	$AVcc \ge 4.5V$
Complinations	Ts	*2	-	-		$AVcc \ge 4.5V$
Sampling time	18	*2	-	-	ns	AVcc < 4.5V
C 1 1 1 *3	TD 1	50		2000		$AVcc \ge 4.5V$
Compare clock cycle* ³	Teck	50	-	2000	ns	AVcc < 4.5V
State transition time to operation permission	Tstt	1.0	-	-	μs	
Power supply current	AVICC	-	0.57	0.72	mA	A/D 1unit operation
(analog + digital)	AVCC	-	0.06	20	μΑ	When A/D stop
Reference power supply current	AVRH	-	1.1	1.96	mA	A/D 1unit operation AVRH=5.5V
(between AVRH to AVSS)	AVKII	-	0.06	4	μΑ	When A/D stop (1unit)
Analog input capacity	Cin	-	-	12.9	pF	
Analog input resistance	Rin			2	kΩ	$AVcc \ge 4.5V$
Analog input resistance	KIII	-	-	3.8	KSZ	AVcc < 4.5V
Interchannel disparity	-	-	-	4	LSB	
Analog port input current	AN0 to AN7	-	-	5	μΑ	
Analog input voltage	AN0 to AN7	AVSS		AVRH	V	
Reference voltage	AVRH	2.7	-	AVCC	V	

^{*1:} Conversion time is the value of sampling time (Ts) + compare time (Tc).

The condition of the minimum conversion time is the value of sampling time: 300ns, the value of sampling time: 700ns (AVcc $\geq 4.5V$).

Ensure that it satisfies the value of sampling time (Ts) and compare clock cycle (Tcck).

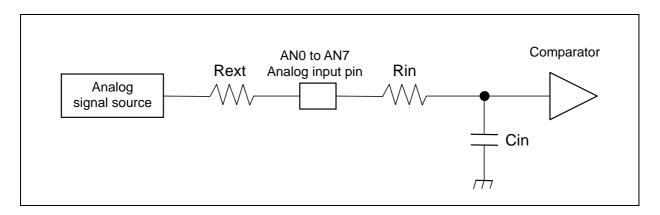
For setting*⁴ of sampling time and compare clock cycle, see "Chapter:A/D Converter" in "FM3 Famliy PERIPHERAL MANUAL Analog Macro Part".

*3: Compare time (Tc) is the value of (Equation 2).

About the APB bus number which A/D Converter is connected to, see "■BLOCK DIAGRAM" in this data sheet.

^{*2:} A necessary sampling time changes by external impedance. Ensure that it set the sampling time to satisfy (Equation 1).

^{*4:} The register setting of the A/D Converter is reflected by the timing of the APB bus clock. Sampling clock and compare clock are set in base clock (HCLK).



(Equation 1) Ts \geq (Rin + Rext) \times Cin \times 9

Ts : Sampling time

Rin : input resistance of A/D = $2k\Omega$ at $4.5 \le AVCC \le 5.5$

input resistance of A/D = $3.8k\Omega$ at $2.7 \le AVCC \le 4.5$

Cin : input capacity of A/D = 12.9pF at $2.7 \le AVCC \le 5.5$

Rext: Output impedance of external circuit

(Equation 2) $Tc = Tcck \times 14$

Tc : Compare time Tcck : Compare clock cycle

· Definition of 12-bit A/D Converter Terms

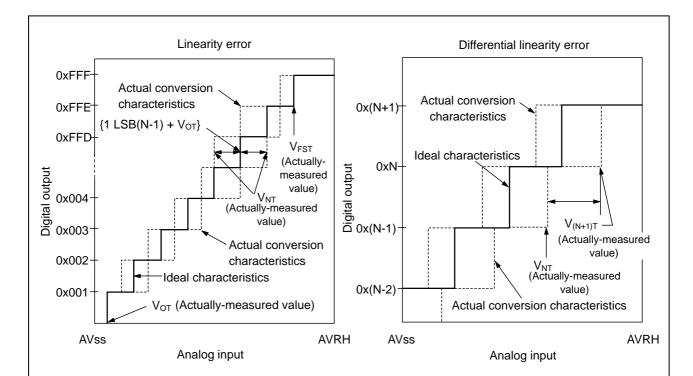
Resolution
 Linearity error
 Analog variation that is recognized by an A/D converter.
 Deviation of the line between the zero-transition point

 $(0b111111111110 \leftarrow \rightarrow 0b111111111111)$ from the actual conversion

characteristics.

• Differential linearity error : Deviation from the ideal value of the input voltage that is required to change

the output code by 1 LSB.



Linearity error of digital output N =
$$\frac{V_{NT} - \{1LSB \times (N-1) + V_{OT}\}}{1LSB}$$
 [LSB]

Differential linearity error of digital output N =
$$\frac{V_{(N+1)T} - V_{NT}}{1LSB}$$
 - 1 [LSB]

$$1LSB = \frac{V_{FST} - V_{OT}}{4094}$$

N : A/D converter digital output value.

 $\begin{array}{lll} V_{OT} & : & \mbox{Voltage at which the digital output changes from 0x000 to 0x001.} \\ V_{FST} & : & \mbox{Voltage at which the digital output changes from 0xFFE to 0xFFF.} \\ V_{NT} & : & \mbox{Voltage at which the digital output changes from 0x(N - 1) to 0xN.} \\ \end{array}$

6. USB Characteristics

 $(Vcc = 2.7V \text{ to } 5.5V, USBVcc = 3.0V \text{ to } 3.6V, Vss = 0V, Ta = -40^{\circ}C \text{ to } + 105^{\circ}C)$

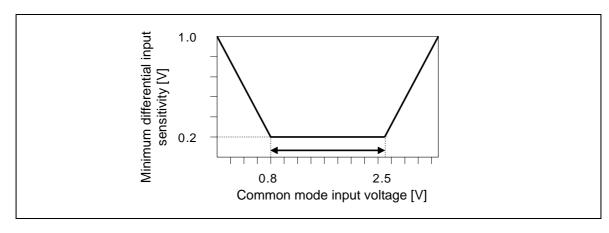
	Parameter	Symbol	Pin	Conditions	\ \ \ \ \	/alue		Remarks
	raiaillelei	Symbol	name	Conditions	Min	Max	Offic	Remarks
	Input "H" level voltage	V_{IH}		-	2.0	USBVcc + 0.3	V	*1
Input	Input "L" level voltage	V_{IL}		-	Vss - 0.3	0.8	V	*1
charact- eristics	Differential input sensitivity	V_{DI}		-	0.2	-	V	*2
	Different common mode input voltage	node V _{CM}		-	0.8	2.5	V	*2
	Output "H" level voltage	V_{OH}	UDP0, UDM0	External pull-down resistance = 15kΩ	2.8	3.6	V	*3
Output	Output "L" level voltage	V_{OL}		External pull-up resistance = 1.5kΩ	0.0	0.3	V	*3
charact-	Crossover voltage	V_{CRS}		-	1.3	2.0	V	*4
erstics	Rise time	t_{FR}		Full-Speed	4	20	ns	*5
	Fall time	t_{FF}		Full-Speed	4	20	ns	*5
	Rise/ fall time matching	t _{FRFM}		Full-Speed	90	111.11	%	*5
	Output impedance	Z_{DRV}		Full-Speed	28	44	Ω	*6
	Rise time	t_{LR}		Low-Speed	75	300	ns	*7
	Fall time	$t_{ m LF}$		Low-Speed	75	300	ns	*7
	Rise/ fall time matching	t_{LRFM}		Low-Speed	80	125	%	*7

^{*1 :} The switching threshold voltage of Single-End-Receiver of USB I/O buffer is set as within V_{IL} (Max) = 0.8V, V_{IH} (Min) = 2.0 V (TTL input standard).

There are some hysteresis to lower noise sensitivity.

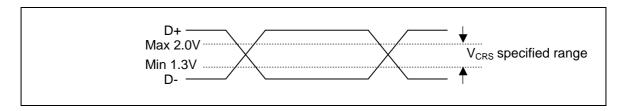
Differential-Receiver has 200 mV of differential input sensitivity when the differential data input is within 0.8 V to 2.5 V to the local ground reference level.

Above voltage range is the common mode input voltage range.

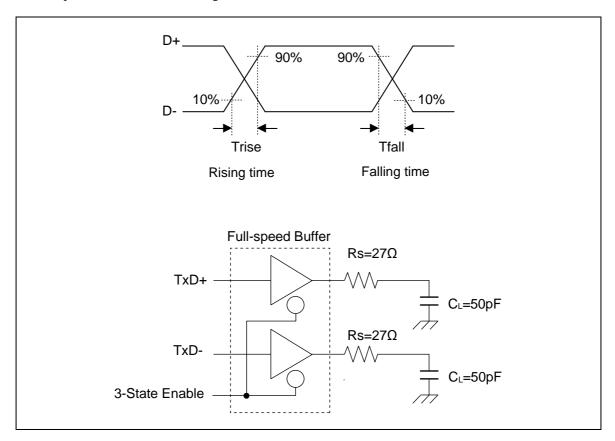


^{*2 :} Use differential-Receiver to receive USB differential data signal.

- *3 : The output drive capability of the driver is below 0.3 V at Low-State (V_{OL}) (to 3.6 V and 1.5 k Ω load), and 2.8 V or above (to the VSS and 1.5 k Ω load) at High-State (V_{OH}).
- *4 : The cross voltage of the external differential output signal (D + /D) of USB I/O buffer is within 1.3 V to 2.0 V.



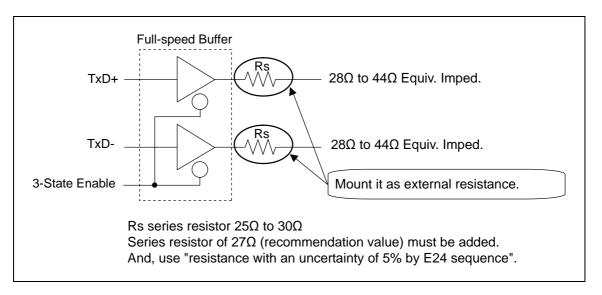
*5 : They indicate rise time (Trise) and fall time (Tfall) of the full-speed differential data signal. They are defined by the time between 10% and 90% of the output signal voltage. For full-speed buffer, Tr/Tf ratio is regulated as within ± 10% to minimize RFI emission.



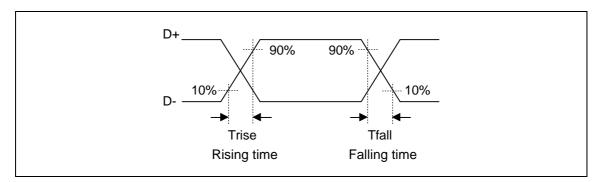
*6 : USB Full-speed connection is performed via twist pair cable shield with $90\Omega \pm 15\%$ characteristic impedance (Differential Mode).

USB standard defines that output impedance of USB driver must be in range from 28Ω to 44Ω . So, discrete series resistor (Rs) addition is defined in order to satisfy the above definition and keep balance.

When using this USB FLS I/O, use it with 25Ω to 30Ω (recommendation value 27Ω) Series resistor Rs.

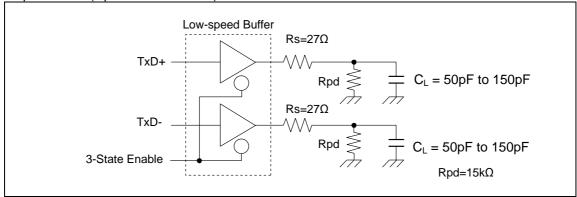


*7: They indicate rise time (Trise) and fall time (Tfall) of the low-speed differential data signal. They are defined by the time between 10% and 90% of the output signal voltage.

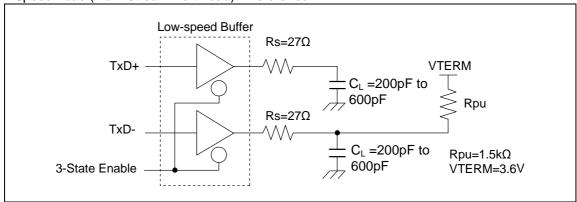


See Figure "• Low-Speed Load (Compliance Load)" for conditions of external load.

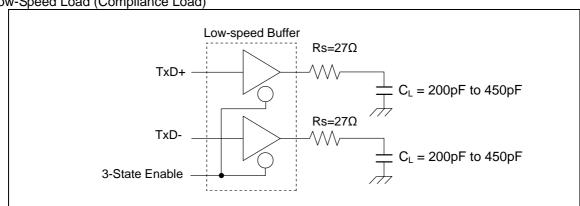
• Low-Speed Load (Upstream Port Load) - Reference 1



• Low-Speed Load (Downstream Port Load) - Reference 2



• Low-Speed Load (Compliance Load)



7. Low-voltage Detection Characteristics

(1) Low-voltage Detection Reset

 $(Ta = -40^{\circ}C \text{ to} + 105^{\circ}C)$

Doromotor	Symbol	ool Conditions		nbol Conditions Value				Unit	Remarks
Parameter Symbol		Conditions	Min	Тур	Max	Offic	Remarks		
Detected voltage	VDL	-	2.25	2.45	2.65	V	When voltage drops		
Released voltage	VDH	-	2.30	2.50	2.70	V	When voltage rises		

(2) Interrupt of Low-voltage Detection

 $(Ta = -40^{\circ}C \text{ to} + 105^{\circ}C)$

Doromotor	Cymbol	Conditions		Value		Unit	Domorko
Parameter	Symbol	Conditions	Min	Тур	Max	Offic	Remarks
Detected voltage	VDL	SVHI = 0000	2.58	2.8	3.02	V	When voltage drops
Released voltage	VDH	3 V HI = 0000	2.67	2.9	3.13	V	When voltage rises
Detected voltage	VDL	SVHI = 0001	2.76	3.0	3.24	V	When voltage drops
Released voltage	VDH	3 V HI = 0001	2.85	3.1	3.34	V	When voltage rises
Detected voltage	VDL	SVHI = 0010	2.94	3.2	3.45	V	When voltage drops
Released voltage	VDH	3 V HI = 0010	3.04	3.3	3.56	V	When voltage rises
Detected voltage	VDL	SVHI = 0011	3.31	3.6	3.88	V	When voltage drops
Released voltage	VDH	3 V HI = 0011	3.40	3.7	3.99	V	When voltage rises
Detected voltage	VDL	SVHI = 0100	3.40	3.7	3.99	V	When voltage drops
Released voltage	VDH	3 V III – 0100	3.50	3.8	4.10	V	When voltage rises
Detected voltage	VDL	SVHI = 0111	3.68	4.0	4.32	V	When voltage drops
Released voltage	VDH	3 V III – U111	3.77	4.1	4.42	V	When voltage rises
Detected voltage	VDL	SVHI = 1000	3.77	4.1	4.42	V	When voltage drops
Released voltage	VDH	3 V III – 1000	3.86	4.2	4.53	V	When voltage rises
Detected voltage	VDL	SVHI = 1001	3.86	4.2	4.53	V	When voltage drops
Released voltage	VDH	3 V III – 1001	3.96	4.3	4.64	V	When voltage rises
LVD stabilization wait time	T_{LVDW}	-	-	-	2240 × tcycp*	μs	

^{*:} t_{CYCP} indicates the APB2 bus clock cycle time.

8. MainFlash Memory Write/Erase Characteristics

 $(Vcc = 2.7V \text{ to } 5.5V, Ta = -40^{\circ}C \text{ to } + 105^{\circ}C)$

Doro	meter		Value		Unit	Remarks
Fala	imeter	Min	Тур	Max	Offic	Remarks
Sector erase	Large Sector		0.7	3.7	c	Includes write time prior to internal
time	Small Sector	-	0.3	1.1	S	erase
Half word (16-write time	Half word (16-bit) write time		12	384	μs	Not including system-level overhead time
Chip erase time		-	3.8	16.2	S	Includes write time prior to internal erase

Erase/write cycles and data hold time

Erase/write cycles (cycle)	Data hold time (year)
1,000	20*
10,000	10*
100,000	5*

^{*:} This value comes from the technology qualification (using Arrhenius equation to translate high temperature measurements into normalized value at + 85°C).

9. WorkFlash Memory Write/Erase Characteristics

 $(Vcc = 2.7V to 5.5V, Ta = -40^{\circ}C to + 105^{\circ}C)$

Parameter	Value			Unit	Remarks
	Min	Тур	Max	Offic	Remarks
Sector erase time	-	0.3	1.5	s	Includes write time prior to internal erase
Half word (16-bit) write time	-	20	384	μs	Not including system-level overhead time
Chip erase time	-	1.2	6	s	Includes write time prior to internal erase

Erase/write cycles and data hold time

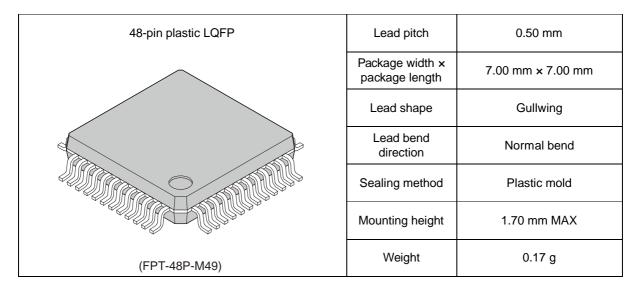
Erase/write cycles (cycle)	Data hold time (year)
1,000	20*
10,000	10*

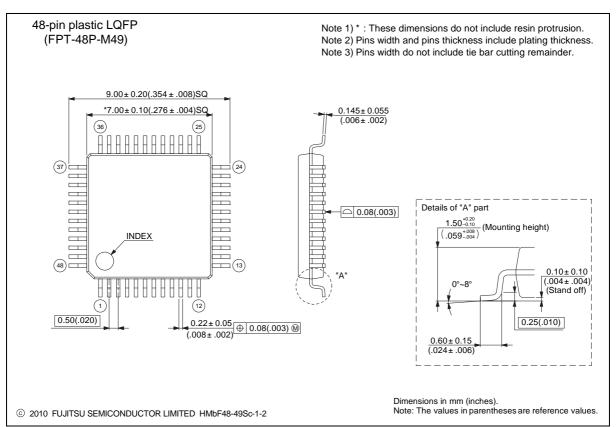
^{*:} This value comes from the technology qualification (using Arrhenius equation to translate high temperature measurements into normalized value at $+85^{\circ}$ C).

■ ORDERING INFORMATION

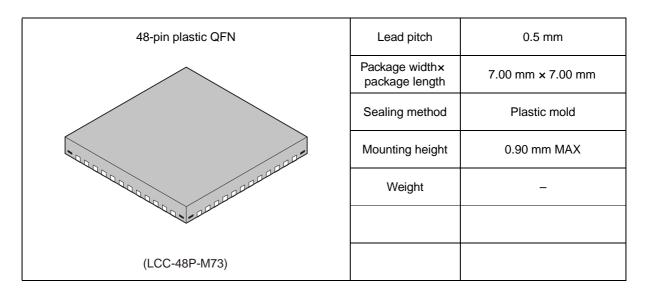
Part number	Package
MB9AF311KPMC	Plastic • LQFP 48-pin
MB9AF312KPMC	(0.5mm pitch), (FPT-48P-M49)
MB9AF311KPMC1	Plastic • LQFP 52-pin
MB9AF312KPMC1	(0.65mm pitch), (FPT-52P-M02)
MB9AF311KQN	Plastic • QFN 48-pin
MB9AF312KQN	(0.5mm pitch), (LCC-48P-M73)

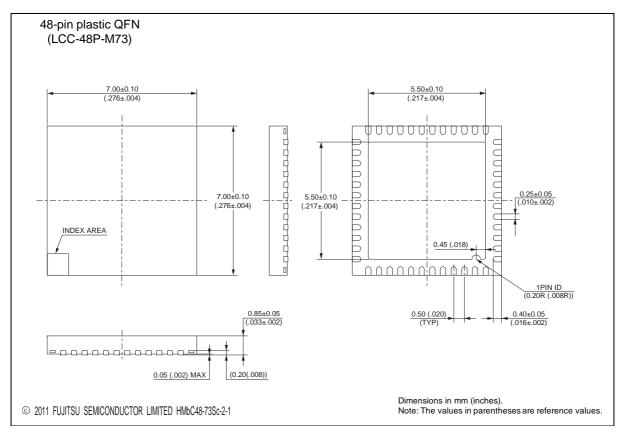
■ PACKAGE DIMENSIONS



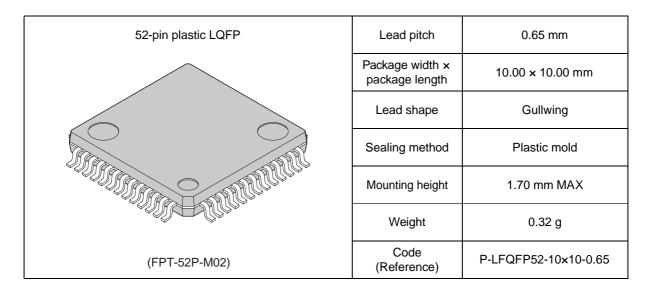


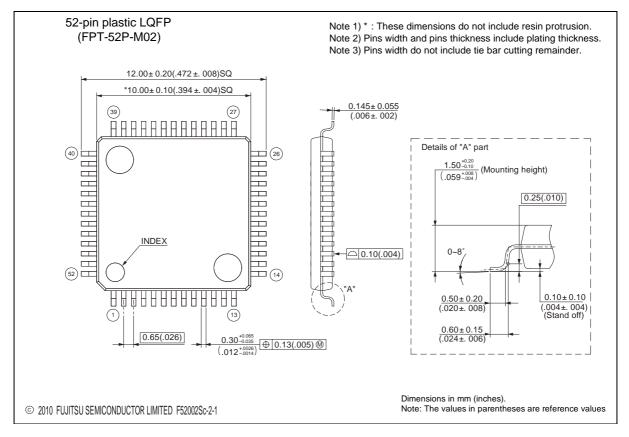
Please check the latest package dimension at the following URL. http://edevice.fujitsu.com/package/en-search/





Please check the latest package dimension at the following URL. http://edevice.fujitsu.com/package/en-search/





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■ MAJOR CHANGES IN THIS EDITION

A change on a page is indicated by a vertical line drawn on the left side of that page.

Page	Section	Change Results
-	-	PRELIMINARY → Data sheet
7	■PRODUCT LINEUP •Function	Added the pin count.
8	■PACKAGES	Revised from "Planning".
23	■I/O CIRCUIT TYPE	Corrected the following description to "TypeB". Digital output → Digital input
34	■BLOCK DIAGRAM	Corrected the following description. • AHB (Max 40MHz) → AHB (Max 42MHz) • APB0 (Max 40MHz) → APB0 (Max 42MHz) • APB1 (Max 40MHz) → APB1 (Max 42MHz) • APB2 (Max 40MHz) → APB2 (Max 42MHz)
45, 46	■ELECTRICAL CHARACTERISTICS 3. DC Characteristics (1) Current Rating	• Revised the value of "TBD". • Corrected the value. - "Power supply current (I_{CCR})" Typ: $60 \rightarrow 50$ - "Power supply current (I_{CCRD})" (RAM hold off) Typ: $45 \rightarrow 30$ - "Power supply current (I_{CCRD})" (RAM hold on) Typ: $48 \rightarrow 33$
61	(9) External Input Timing	Revised the value of "TBD".
66	5. 12-bit A/D Converter *Electrical characteristics for the A/D converter	 Deleted"(Preliminary value)". Corrected the value of "Compare clock cycle". Max: 10000 → 2000
74	8. MainFlash Memory Write/Erase Characteristics Erase/write cycles and data hold time	Deleted"(targeted value)".
7-7	9. WorkFlash Memory Write/Erase Characteristics Erase/write cycles and data hold time	

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